



ACE25AA400G Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Description

The ACE25AA400G is 4M-bit Serial flash supports the standard Serial Peripheral Interface (SPI). and supports the Dual/Quad SPI: Serial Clock, Chip Select, Serial Data I/O0 (SI), I/O1 (SO), I/O2 (WP#), and I/O3 (HOLD#). The Dual I/O data is transferred with speed of 216Mbits/s and the Quad I/O & Quad output data is transferred with speed of 432Mbits/s.

Features

- 4M-bit Serial Flash
 - 512K-byte
 - 256 bytes per programmable page
- Standard, Dual, Quad SPI
 - Standard SPI: SCLK, CS#, SI, SO, WP#, HOLD#
 - Dual SPI: SCLK, CS#, IO0, IO1, WP#, HOLD#
 - Quad SPI: SCLK, CS#, IO0, IO1, IO2, IO3
- Flexible Architecture
 - Sector of 4K-byte
 - Block of 32/64k-byte
- Package Options
 - All Pb-free packages are compliant RoHS, Halogen-Free and REACH.
- Temperature Range & Moisture Sensitivity Level
 - Industrial Level Temperature. (-40°C to +85°C), MSL3
- Low Power Consumption
 - 20mA maximum active current
 - 0.05uA maximum power down current
- Single Power Supply Voltage: Full voltage range:2.7~3.6V
- Minimum 100,000 Program/Erase Cycle
- High Speed Clock Frequency
 - 108MHz for fast read with 30PF load
 - Dual I/O Data transfer up to 216Mbits/s
 - Quad I/O Data transfer up to 432Mbits/s
- Program/Erase Speed
 - Page Program time: 0.4ms typical
 - Sector Erase time: 60ms typical
 - Block Erase time: 0.15/0.25s typical
 - Chip Erase time: 1.25s typical



ACE25AA400G

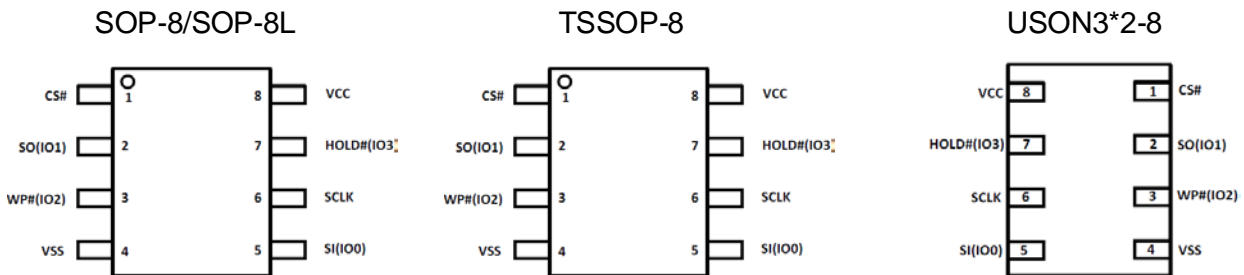
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- Software/Hardware Write Protection
Write protect all/portion of memory via software
Enable/Disable protection with WP# Pin
Top or Bottom, Sector or Block selection
- Advanced security Features
4*256-Byte Security Registers With OTP Lock
- Support SFDP & Unique ID

Absolute Maximum Ratings

| Parameter | Value | Unit |
|-------------------------------|-------------|------|
| Ambient Operating Temperature | -40 to 85 | °C |
| Storage Temperature | -65 to 150 | °C |
| Output Short Circuit Current | 200 | mA |
| Applied Input /Output Voltage | -0.5 to 4.0 | V |
| VCC | -0.5 to 4.0 | V |

Packaging Type



Pin Configurations

| Pin Name | I/O | Functions |
|------------|-----|---|
| CS# | I | Chip Select Input |
| SO(IO1) | I/O | Data Output(Data Input Output 1) |
| WP#(IO2) | I/O | Write Protect Input (Data Input Output 2) |
| VSS | | Ground |
| SI(IO0) | I/O | Data Input(Data Input Output 0) |
| SCLK | I | Serial Clock Input |
| HOLD#(IO3) | I/O | Hold Input (Data Input Output 3) |
| VCC | | Power Supply |

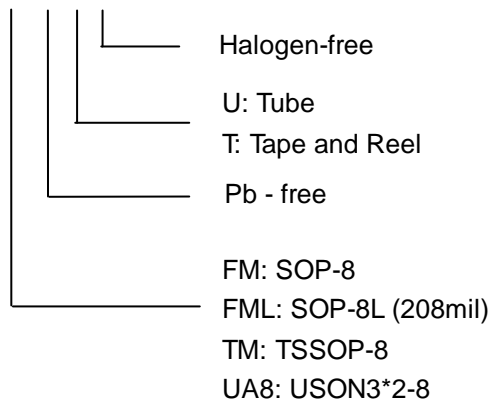


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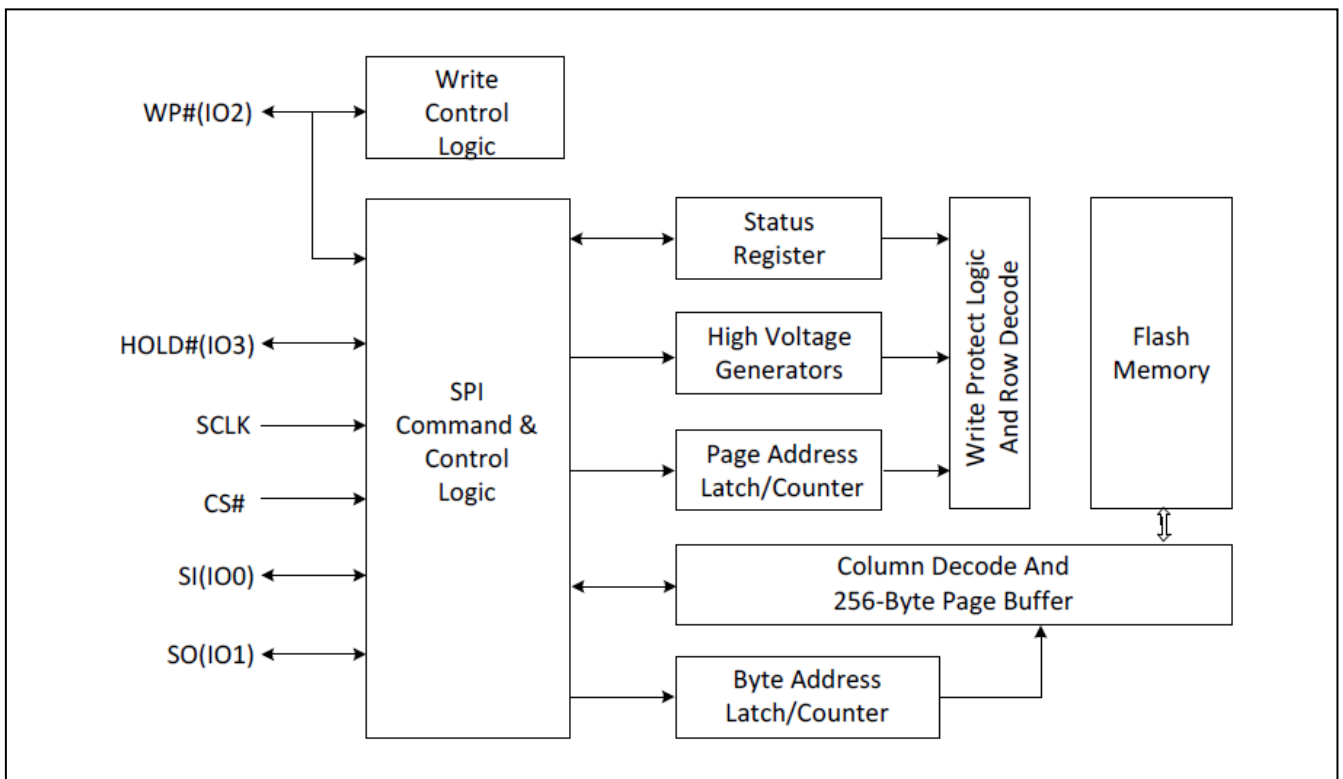
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Ordering information

ACE25AA400G XX + X H



Block Diagram





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Uniform Block Sector Architecture

ACE25AA400G 64K Bytes Block Sector Architecture

| Block | Sector | Address Range | |
|-------|--------|---------------|---------|
| 7 | 127 | 07F000H | 07FFFFH |
| | | | |
| | 112 | 070000H | 070FFFH |
| 6 | 111 | 06F000H | 06FFFFH |
| | | | |
| | 96 | 060000H | 060FFFH |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| 2 | 47 | 02F000H | 02FFFFH |
| | | | |
| | 32 | 020000H | 020FFFH |
| 1 | 31 | 01F000H | 01FFFFH |
| | | | |
| | 16 | 010000H | 010FFFH |
| 0 | 15 | 00F000H | 00FFFFH |
| | | | |
| | 0 | 000000H | 000FFFH |



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Device Operation

The ACE25AA400G features a serial peripheral interface on 4 signals bus: Serial Clock (SCLK), Chip Select (CS#), Serial Data Input (SI) and Serial Data Output (SO). Both SPI bus mode 0 and 3 are supported. Input data is latched on the rising edge of SCLK and data shifts out on the falling edge of SCLK.

Note: “WP#” & “HOLD#” pin require external pull-up

Dual SPI

The ACE25AA400G supports Dual SPI operation when using the “Dual Output Fast Read” and “Dual I/O Fast Read” (3BH and BBH) commands. These commands allow data to be transferred to or from the device at two times the rate of the standard SPI. When using the Dual SPI command the SI and SO pins become bidirectional I/O pins: IO0 and IO1.

Note: “WP#” & “HOLD#” pin require external pull-up

Quad SPI

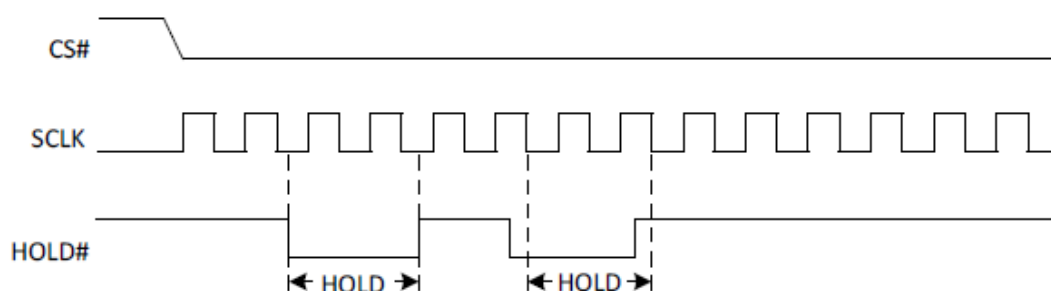
The ACE25AA400G supports Quad SPI operation when using the “Quad Output Fast Read”, “Quad I/O Fast Read”, “Quad I/O Word Fast Read” (6BH, EBH, E7H) commands. These commands allow data to be transferred to or from the device at four times the rate of the standard SPI. When using the Quad SPI command the SI and SO pins become bidirectional I/O pins: IO0 and IO1, and WP# and HOLD# pins become IO2 and IO3. Quad SPI commands require the non-volatile Quad Enable bit (QE) in Status Register to be set .

Hold

The HOLD# signal goes low to stop any serial communications with the device, but doesn't stop the operation of write status register, programming, or erasing in progress .

The operation of HOLD, need CS# keep low, and starts on falling edge of the HOLD# signal, with SCLK signal being low (if SCLK is not being low, HOLD operation will not start until SCLK being low). The HOLD condition ends on rising edge of HOLD# signal with SCLK being low (If SCLK is not being low, HOLD operation will not end until SCLK being low).

The SO is high impedance, both SI and SCLK don't care during the HOLD operation, if CS# drives high during HOLD operation, it will reset the internal logic of the device. To re-start communication with chip, the HOLD# must be at high and then CS# must be at low.





Data Protection

The ACE25AA400G provides the following data protection methods:

Write Enable (WREN) command: The WREN command is set the Write Enable Latch bit (WEL). The WEL bit will return to reset by the following situation:

- Power-Up
- Write Disable (WRDI)
- Write Status Register (WRSR)
- Page Program (PP)
- Sector Erase (SE) / Block Erase (BE) / Chip Erase (CE)

Software Protection Mode:

- The Block Protect (BP3, BP2, BP1, BP0) bits define the section of the memory array that can be read but not change

Hardware Protection Mode:

- WP# going low to protected the BP0~BP3 bits and SRP bit

Deep Power-Down Mode:

- In Deep Power-Down Mode, all commands are ignored except the Release from Deep Power-Down Mode command

Table 1.ACE25AA400G Protected Area Sizes (CMP=0)

| Status Register Contents | | | | Protect Level | Protected Block |
|--------------------------|-----|-----|-----|---------------|-----------------|
| BP3 | BP2 | BP1 | BP0 | | |
| 0 | 0 | 0 | 0 | 0(none) | None |
| 0 | 0 | 0 | 1 | 1(1 block) | Block 7 |
| 0 | 0 | 1 | 0 | 2(2 blocks) | Block 6-7 |
| 0 | 0 | 1 | 1 | 3(4 blocks) | Block 4-7 |
| 0 | 1 | 0 | 0 | 4(8 blocks) | protected all |

Table 1.1ACE25AA400G Protected Area Sizes (CMP=1)

| Status Register Contents | | | | Protect Level | Protected Block |
|--------------------------|-----|-----|-----|---------------|-----------------|
| BP3 | BP2 | BP1 | BP0 | | |
| 0 | 0 | 0 | 0 | 0(none) | None |
| 0 | 0 | 0 | 1 | 1(1 block) | Block 0 |
| 0 | 0 | 1 | 0 | 2(2 blocks) | Block 0-1 |
| 0 | 0 | 1 | 1 | 3(4 blocks) | Block 0-3 |
| 0 | 1 | 0 | 0 | 4(8 blocks) | Block 0-7 |



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Status Register

| | | | | | | | |
|----------|-----|----------|----------|----------|-----|----|----------|
| S15 | S14 | S13 | S12 | S11 | S10 | S9 | S8 |
| Reserved | CMP | Reserved | Reserved | Reserved | LB | QE | Reserved |

| | | | | | | | |
|-----|----------|-----|-----|-----|-----|-----|-----|
| S7 | S6 | S5 | S4 | S3 | S2 | S1 | S0 |
| SRP | Reserved | BP3 | BP2 | BP1 | BP0 | WEL | WIP |

The status and control bits of the Status Register are as follows:

WIP bit.

The Write In Progress (WIP) bit indicates whether the memory is busy in program/erase/write status register progress. When WIP bit sets to 1, the device is busy in program/erase/write status register progress, When WIP bit sets 0, means the device is not in program/ erase/ write status register progress.

WEL bit.

The Write Enable Latch (WEL) bit indicates the status of the internal Write Enable Latch. When set to 1 the internal Write Enable Latch is set. When set to 0, the internal Write Enable Latch is reset and no Write Status Register, Program or Erase command is accepted.

BP3,BP2, BP1,BP0 bits.

The Block Protect (BP3, BP2, BP1, BP0) bits are non-volatile. They define the size of the area to be software protected against Program and Erase commands. These bits are written with the Write Status Register (WRSR) command. When the Block Protect (BP3, BP2, BP1, BP0) bits are set to 1, the relevant memory area (as defined in Table1) becomes protected against Page Program (PP), Sector Erase (SE) and Block Erase (BE) commands. The Block Protect (BP3, BP2, BP1, BP0) bits can be written provided that the Hardware Protected mode has not been set. The Chip Erase (CE) command is executed, if the Block Protect (BP3, BP2, BP1, BP0) bits are all 0.

SRP bit.

The Status Register Protect (SRP) bit is a non-volatile Read/Write bit in the status register. The SRP bit controls the method of write protection: software protection, hardware protection, power supply lock-down or one time programmable protection.

| SRP | WP# | Status Register | Description |
|-----|-----|----------------------|--|
| 0 | X | Software Protected | The Status Register can be written to after a Write Enable command, WEL=1.(Default) |
| 1 | 0 | Hardware Protected | WP#=0, the Status Register locked and cannot be written until the next power-up. |
| 1 | 1 | Hardware Unprotected | WP#=1, the Status Register is unlocked and can be written after a Write Enable command, WEL=1. |



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QE bit.

The Quad Enable (QE) bit is a non-volatile Read/Write bit in the Status Register that allows Quad operation. When the QE bit is set to 0 (Default) the WP# pin and HOLD# pin are enable. When the QE bit is set to 1, the Quad IO2 and IO3 pins are enabled. (The QE bit should never be set to 1 during standard SPI or Dual SPI operation if the WP# or HOLD# pins are tied directly to the power supply or ground).

LB bit.

The LB bit is a non-volatile One Time Program (OTP) bit in Status Register (S10) that provide the write protect control and status to the Security Registers. The default state of LB is 0, the security registers are unlocked. LB can be set to 1 using the Write Register instruction. LB is One Time Programmable, once it's set to 1, the Security Registers will become read-only permanently.

CMP bit.

The CMP bit is a non-volatile Read/Write bit in the Status Register (S14). It is used in conjunction with the BP3-BP0 bits to provide more flexibility for the array protection. Please see the Status registers Memory Protection table for details. The default setting is CMP=0.

Commands Description

All commands, addresses and data are shifted in and out of the device, beginning with the most significant bit on the first rising edge of SCLK after CS# is driven low. Then, the one-byte command code must be shifted in to the device, most significant bit first on SI, each bit being latched on the rising edges of SCLK. See Table2, every command sequence starts with a one-byte command code. Depending on the command, this might be followed by address bytes, or by data bytes, or by both or none. CS# must be driven high after the last bit of the command sequence has been shifted in. For the command of Read, Fast Read, Read Status Register, and Read Device ID, the shifted-in command sequence is followed by a data-out sequence. CS# can be driven high after any bit of the data-out sequence is being shifted out.

For the command of Page Program, Sector Erase, Block Erase, Chip Erase, Write Status Register, Write Enable, Write Disable, CS# must be driven high exactly at a byte boundary, otherwise the command is rejected. That is CS# must driven high when the number of clock pulses after CS# being driven low is an exact multiple of eight. For Page Program, if at any time the input byte is not a full byte, nothing will happen and WEL will not be reset.



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Table2. Commands

| Command Name | Byte1 | Byte2 | Byte3 | Byte4 | Byte5 | Byte6 | n-Bytes |
|---|-------|--------------------|-------------------|-------------|-------------|-------------|--------------|
| Write Enable | 06H | | | | | | |
| Write Enable for Volatile Status Register | 50H | | | | | | |
| Write Disable | 04H | | | | | | |
| Read Status Register | 05H | (S7-S0) | | | | | (continuous) |
| Read Status Register-1 | 35H | (S15-S8) | | | | | (continuous) |
| Write Status Register | 01H | (S7-S0) | (S15-S8) | | | | (continuous) |
| Read Data | 03H | A23-A16 | A15-A8 | A7-A0 | (D7-D0) | (Next byte) | (continuous) |
| Fast Read | 0BH | A23-A16 | A15-A8 | A7-A0 | dummy | (D7-D0) | (continuous) |
| Dual Output Fast Read | 3BH | A23-A16 | A15-A8 | A7-A0 | dummy | (D7-D0)(1) | (continuous) |
| Dual I/O Fast Read | BBH | A23-A8(2) | A7-A0 M7-M0(2) | (D7-D0)(1) | | | (continuous) |
| Quad Output Fast Read | 6BH | A23-A16 | A15-A8 | A7-A0 | dummy | (D7-D0)(3) | (continuous) |
| Quad I/O Fast Read | EBH | A23-A0 M7-M0(4) | Dummy(5) | (D7-D0)(3) | | | (continuous) |
| Quad I/O Word Fast Read | E7H | A23-A0 M7-M0(4) | Dummy(6) | (D7-D0)(3) | | | (continuous) |
| Continuous Read Reset | FFH | | | | | | |
| Page Program | 02H | A23-A16 | A15-A8 | A7-A0 | (D7-D0) | (Next byte) | |
| Quad Page Program | 32H | A23-A16 | A15-A8 | A7-A0 | (D7-D0)(3) | | |
| Quad I/O PP | 38H | A23-A0 D7-D0 | (D39-D8) | (Next byte) | (Next byte) | | |
| Sector Erase | 20H | A23-A16 | A15-A8 | A7-A0 | | | |



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| | | | | | | | |
|--|--------|-------------------|--------------------|----------------------|--------------|-------------|--------------|
| Block Erase(32KB) | 52H | A23-A16 | A15-A8 | A7-A0 | | | |
| Block Erase(64KB) | D8H | A23-A16 | A15-A8 | A7-A0 | | | |
| Chip Erase | C7/60H | | | | | | |
| Deep Power-Down | B9H | | | | | | |
| Release From Deep Power-Down, And Read Device ID | ABH | dummy | dummy | dummy | (DID7-DID0) | | (continuous) |
| Release From Deep Power-Down | ABH | | | | | | |
| Manufacturer/Device ID | 90H | dummy | dummy | 00H | (MID7- MID0) | (DID7-DID0) | (continuous) |
| Manufacturer/Device ID by Dual I/O | 92H | A23-A8 | A7-A0, M[7:0] | (M7-M0) (ID7-ID0) | | | (continuous) |
| Manufacturer/Device ID by Quad I/O | 94H | A23-A0, M[7:0] | dummy | (M7-M0) (ID7-ID0) | | | |
| Read Serial Flash Discoverable Parameters | 5AH | A23-A16 | A15-A8 | A7-A0 | dummy | (D7-D0) | (continuous) |
| Read Unique ID | 5AH | 00h | 01h | 94h | dummy | (D7-D0) | (continuous) |
| Read Identification | 9FH | (MID7- MID0) | (JDID15-J DID8) | (JDID7-JDI D0) | | | (continuous) |
| Erase Security Register(8) | 44H | A23-A16 | A15-A8 | A7-A0 | | | |
| Program Security Register(8) | 42H | A23-A16 | A15-A8 | A7-A0 | (D7-D0) | (Next byte) | |
| Read Security Register(8) | 48H | A23-A16 | A15-A8 | A7-A0 | dummy | (D7-D0) | |
| Enable Reset | 66H | | | | | | |
| Reset | 99H | | | | | | |

Notes:

1. Dual Output data

IO0 = (D6, D4, D2, D0) IO1 = (D7, D5, D3, D1)



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2. Dual Input Address
 IO0 = A22, A20, A18, A16, A14, A12, A10, A8, A6, A4, A2, A0, M6, M4, M2, M0
 IO1 = A23, A21, A19, A17, A15, A13, A11, A9, A7, A5, A3, A1, M7, M5, M3, M1
3. Quad Output Data
 IO0 = (D4, D0,)
 IO1 = (D5, D1,)
 IO2 = (D6, D2,)
 IO3 = (D7, D3,)
4. Quad Input Address
 IO0 = A20, A16, A12, A8, A4, A0, M4, M0
 IO1 = A21, A17, A13, A9, A5, A1, M5, M1
 IO2 = A22, A18, A14, A10, A6, A2, M6, M2
 IO3 = A23, A19, A15, A11, A7, A3, M7, M3
5. Quad I/O Fast Read Data
 IO0 = (x, x, x, x, D4, D0,...)
 IO1 = (x, x, x, x, D5, D1,...)
 IO2 = (x, x, x, x, D6, D2,...)
 IO3 = (x, x, x, x, D7, D3,...)
6. Quad I/O Word Fast Read Data
 IO0 = (x, x, D4, D0,...)
 IO1 = (x, x, D5, D1,...)
 IO2 = (x, x, D6, D2,...)
 IO3 = (x, x, D7, D3,...)
7. Quad I/O Word Fast Read Data: the lowest address bit must be 0
8. Security Registers Address :
 Security Register1: A23-A16=00H, A15-A8=01H, A7-A0= Byte Address;
 Security Register2: A23-A16=00H, A15-A8=02H, A7-A0= Byte Address;
 Security Register3: A23-A16=00H, A15-A8=03H, A7-A0= Byte Address.

ID Definitions

| Operation Code | M7-M0 | ID15-ID8 | ID7-ID0 |
|----------------|-------|----------|---------|
| 9FH | 0E | 40 | 14 |
| 90H | 0E | | 13 |
| ABH | | | 13 |



Write Enable (WREN) (06H)

The Write Enable (WREN) command is for setting the Write Enable Latch (WEL) bit. The Write Enable Latch (WEL) bit must be set prior to every Page Program (PP), Sector Erase (SE), Block Erase (BE), Chip Erase (CE) and Write Status Register (WRSR) command. The Write Enable (WREN) command sequence: CS# goes low, sending the Write Enable command, CS# goes high.

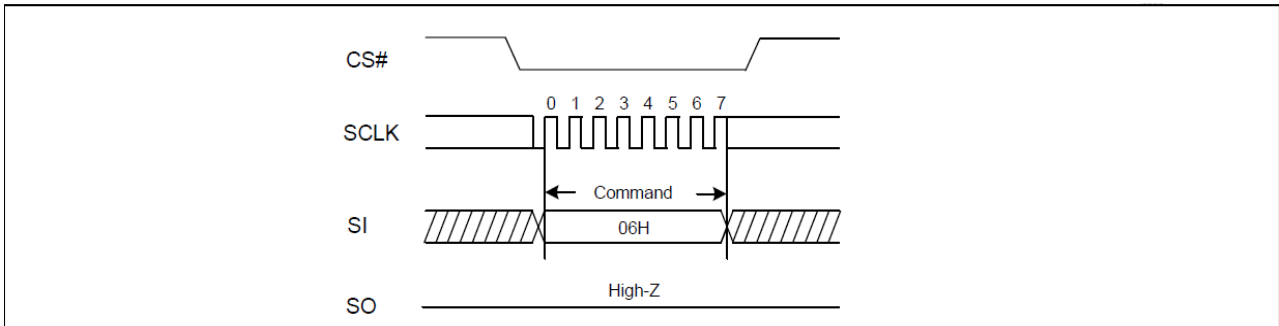


Figure1. Write Enable Sequence Diagram

Write Enable for Volatile Status Register (50H)

The non-volatile Status Register bits can also be written to as volatile bits. This gives more flexibility to change the system configuration and memory protection schemes quickly without waiting for the typical non-volatile bit write cycles or affecting the endurance of the Status Register non-volatile bits. The Write Enable for Volatile Status Register command must be issued prior to a Write Status Register command and any other commands can't be inserted between them. Otherwise, Write Enable for Volatile Status Register will be cleared. The Write Enable for Volatile Status Register command will not set the Write Enable Latch bit, it is only valid for the Write Status Register command to change the volatile Status Register bit values.

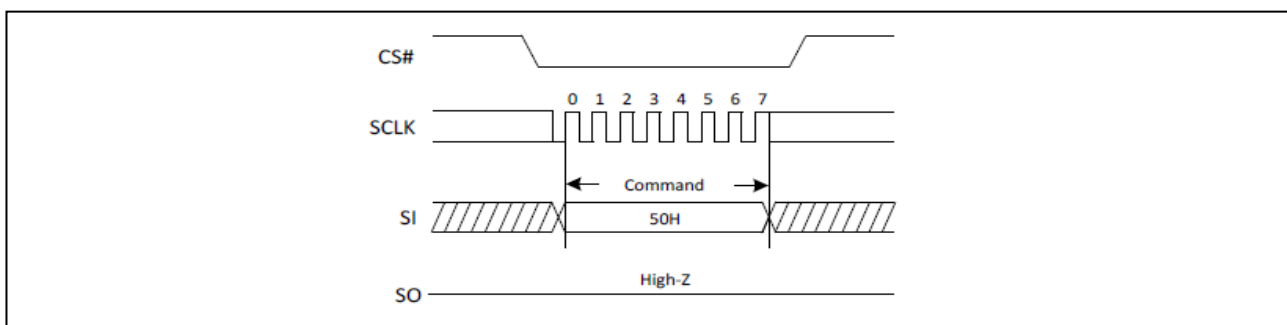


Figure2. Write Enable for Volatile Status Register Sequence Diagram



Write Disable (WRDI) (04H)

The Write Disable command is for resetting the Write Enable Latch (WEL) bit. The Write Disable command sequence: CS# goes low Send Write Disable command CS# goes high. The WEL bit is reset by following condition: Power-up and upon completion of the Write Status Register, Page Program, Sector Erase, Block Erase and Chip Erase commands.

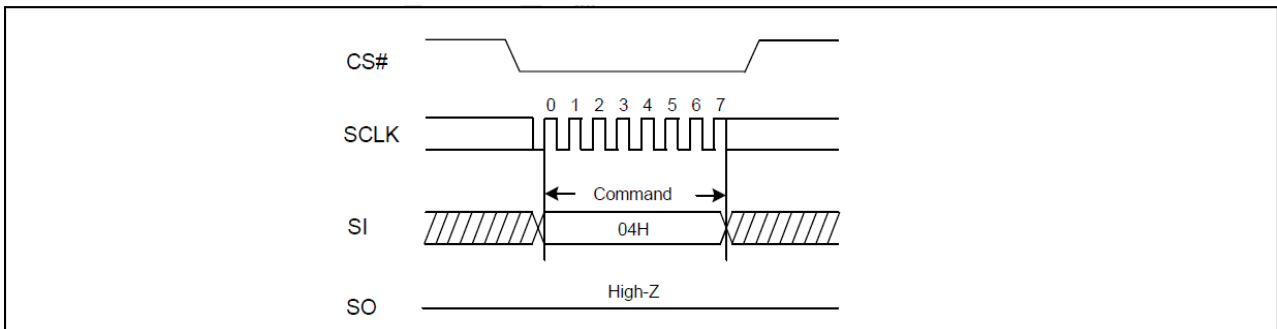


Figure3. Write Disable Sequence Diagram

Read Status Register (RDSR) (05H or 35H)

The Read Status Register (RDSR) command is for reading the Status Register. The Status Register may be read at any time, even while a Program, Erase or Write Status Register cycle is in progress. When one of these cycles is in progress, it is recommended to check the Write In Progress (WIP) bit before sending a new command to the device. It is also possible to read the Status Register continuously. For command code "05H", the SO will output Status Register bits S7~S0. The command code "35H", the SO will output Status Register bits S15~S8.

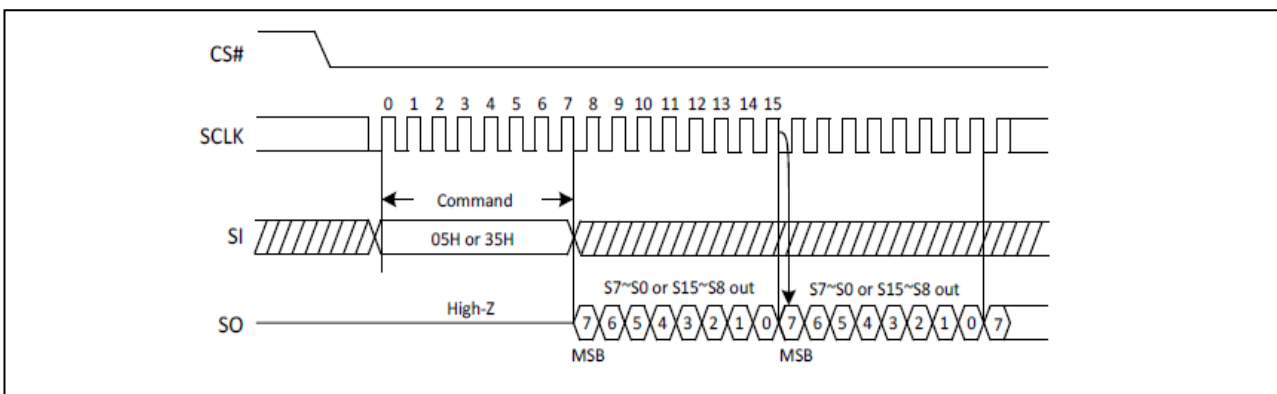


Figure4. Read Status Register Sequence Diagram

Write Status Register (WRSR) (01H)

The Write Status Register (WRSR) command allows new values to be written to the Status Register. Before it can be accepted, a Write Enable (WREN) command must previously have been executed. After the Write Enable (WREN) command has been decoded and executed, the device sets the Write Enable Latch (WEL).

The Write Status Register (WRSR) command has no effect on S15, S1 and S0 of the Status Register.



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CS# must be driven high after the eighth bit of the data byte has been latched in. If not, the Write Status Register (WRSR) command is not executed. If CS# is driven high after eighth bit of the data byte, the CMP and QE bit will be cleared to 0. As soon as CS# is driven high, the self-timed Write Status Register cycle (whose duration is t_W) is initiated. While the Write Status Register cycle is in progress, the Status Register can still be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Write Status Register cycle, and is 0 when it is completed. When the cycle is completed, the Write Enable Latch (WEL) is reset.

The Write Status Register (WRSR) command allows the user to change the values of the Block Protect (BP3, BP2, BP1, BP0) bits, to define the size of the area that is to be treated as read-only, as defined in Table1. The Write Status Register (WRSR) command also allows the user to set or reset the Status Register Protect (SRP) bit in accordance with the Write Protect (WP#) signal. The Status Register Protect (SRP) bit and Write Protect (WP#) signal allow the device to be put in the Hardware Protected Mode. The Write Status Register (WRSR) command is not executed once the Hardware Protected Mode is entered.

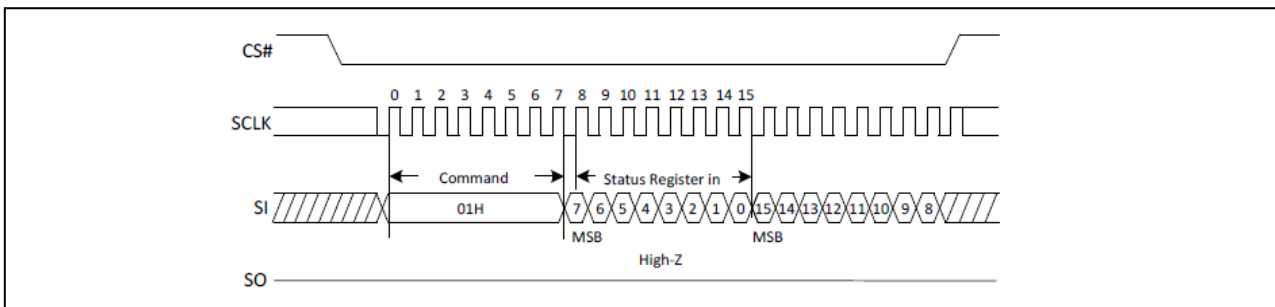


Figure5. Write Status Register Sequence Diagram

Read Data Bytes (READ) (03H)

The Read Data Bytes (READ) command is followed by a 3-byte address (A23-A0), each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency f_R , during the falling edge of SCLK. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. Therefore, the whole memory can, therefore, be read with a single Read Data Bytes (READ) command. Any Read Data Bytes (READ) command, while an Erase, Program or Write cycle is in progress, is rejected without having any effects on the cycle that is in progress.

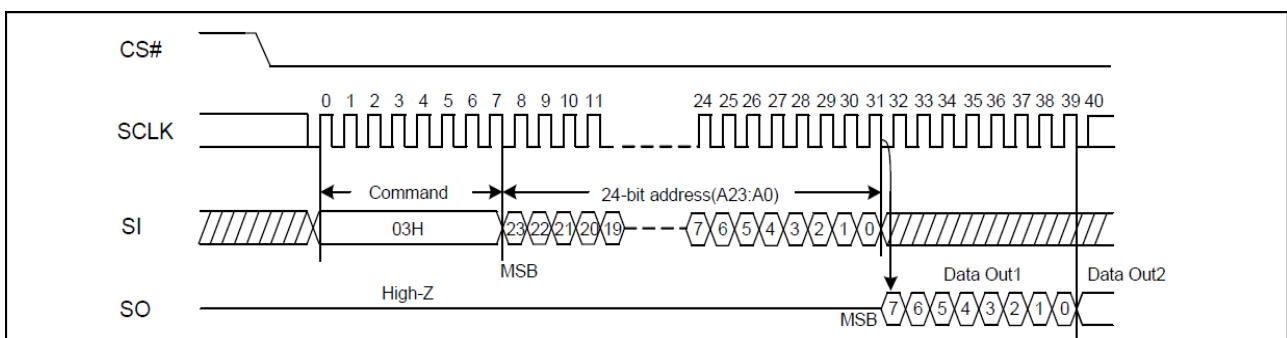


Figure6. Read Data Bytes Sequence Diagram



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Read Data Bytes At Higher Speed (Fast Read)(0BH)

The Read Data Bytes at Higher Speed (Fast Read) command is for fast reading data out. It is followed by a 3-byte address (A23-A0) and a dummy byte, each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency f_C , during the falling edge of SCLK. The first byte address can be at any location. The address is automatically incremented to the next address after each byte of data is shifted out.

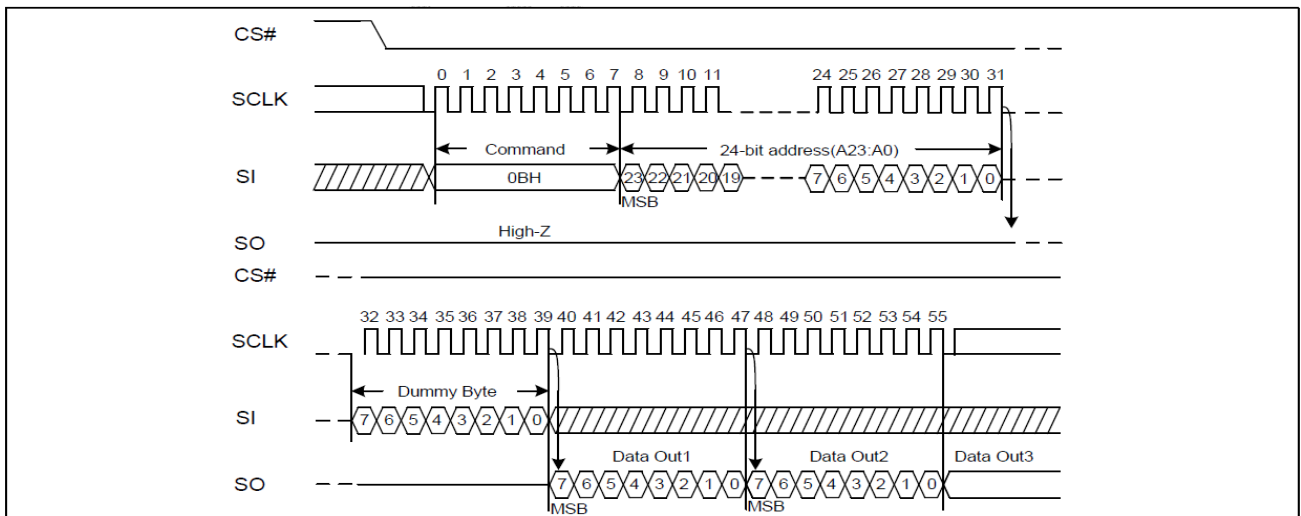


Figure7. Read Data Bytes at Higher Speed Sequence Diagram

Dual Output Fast Read (3BH)

The Dual Output Fast Read command is followed by 3-byte address (A23-A0) and a dummy byte, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 2-bit per clock cycle from SI and SO. The command sequence is shown in Figure 8. The first byte addressed can be at any location. The address is automatically incremented to the next address after each byte of data is shifted out.

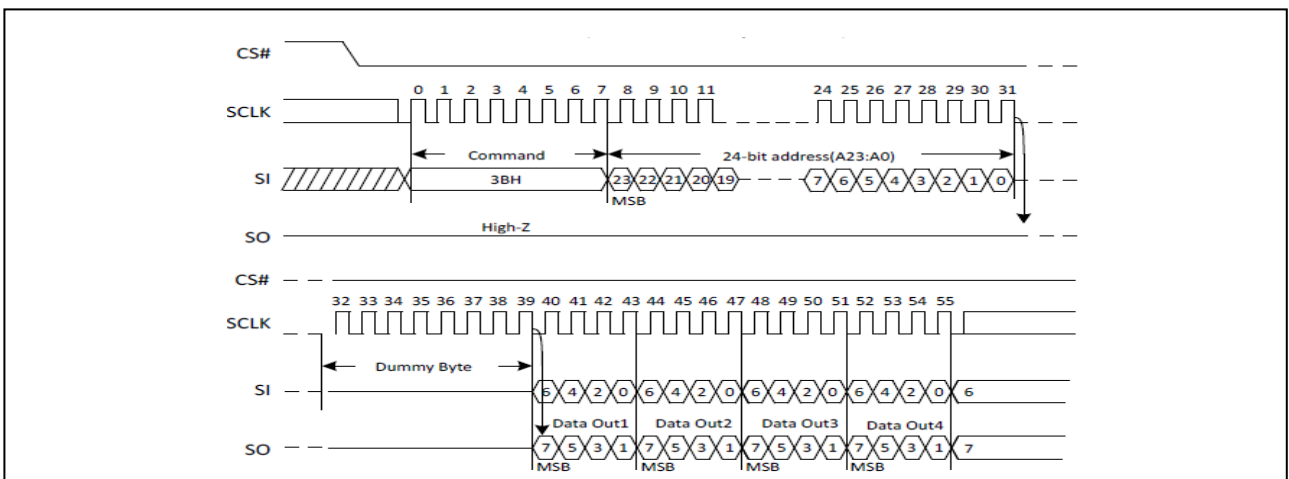


Figure8. Dual Output Fast Read Sequence Diagram



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Quad Output Fast Read (6BH)

The Quad Output Fast Read command is followed by 3-byte address (A23-A0) and a dummy byte, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 4-bit per clock cycle from IO3, IO2, IO1 and IO0. The command sequence is shown in Figure 9. The first byte addressed can be at any location. The address is automatically incremented to the next address after each byte of data is shifted out.

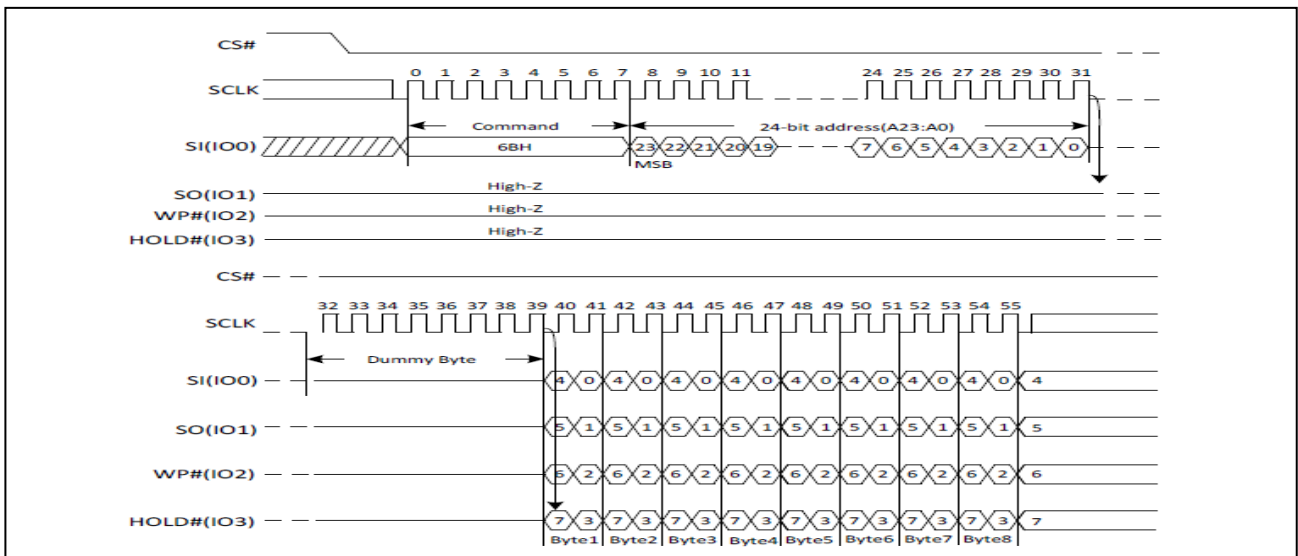


Figure9. Quad Output Fast Read Sequence Diagram

Dual I/O Fast Read(BBH)

The Dual I/O Fast Read command is similar to the Dual Output Fast Read command but with the capability to input the 3-byte address (A23-0) and a “Continuous Read Mode” byte 2-bit per clock by SI and SO, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 2-bit per clock cycle from SI and SO. The command sequence is shown in Figure 10. The first byte addressed can be at any location. The address is automatically incremented to the next address after each byte of data is shifted out.

Dual I/O Fast Read with “Continuous Read Mode”

The Dual I/O Fast Read command can further reduce command overhead through setting the “Continuous Read Mode” bits (M7- 0) after the input 3-byte address (A23-A0). If the “Continuous Read Mode” bits (M5- 4) = (1, 0), then the next Dual I/O Fast Read command (after CS# is raised and then lowered) does not require the BBH command code. The command sequence is shown in figure 11. If the “Continuous Read Mode” bits (M5- 4) do not equal (1, 0), the next command requires the first BBH command code, thus returning to normal operation. A “Continuous Read Mode” Reset command can be used to reset (M5- 4) before issuing normal command.



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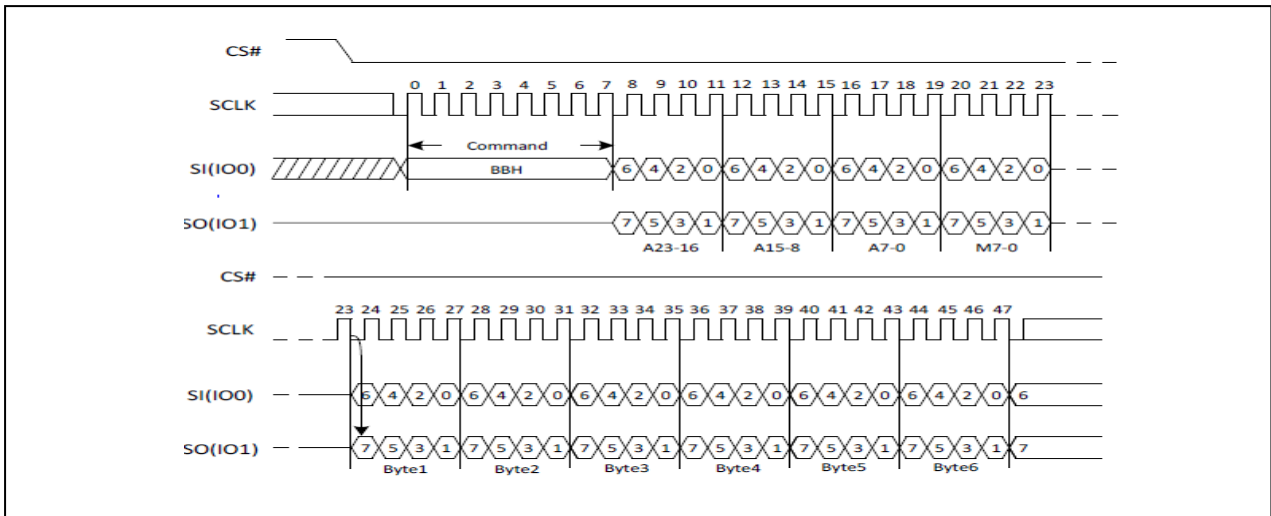


Figure10. Dual I/O Fast Read Sequence Diagram (M5-4# (1, 0))

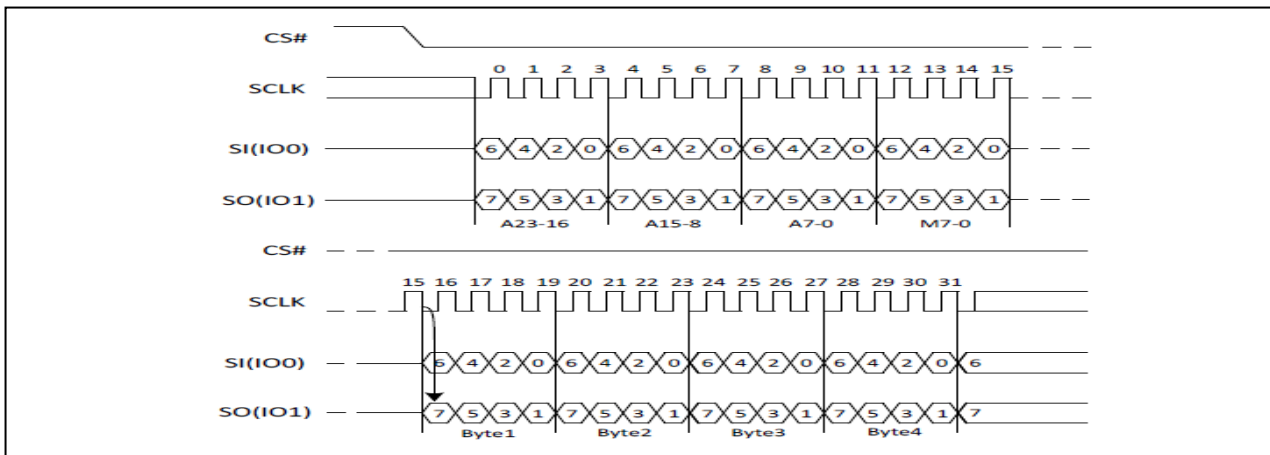


Figure11. Dual I/O Fast Read Sequence Diagram (M5-4= (1, 0))

Quad I/O Fast Read(EBH)

The Quad I/O Fast Read command is similar to the Dual I/O Fast Read command but with the capability to input the 3-byte address (A23-0) and a “Continuous Read Mode” byte and 4-dummy clock 4-bits per clock by IO0, IO1, IO3, IO4, each bit being latched in during the rising edge of SCLK, then the memory contents are shifted out 4-bit per clock cycle from IO0, IO1, IO2, IO3. The command sequence is shown in Figure 12. The first byte addressed can be at any location. The address is automatically incremented to the next address after each byte of data is shifted out. The Quad Enable bit (QE) of Status Register (S9) must be set to enable for the Quad I/O Fast read command.



Quad I/O Fast Read with “Continuous Read Mode”

The Quad I/O Fast Read command can further reduce command overhead through setting the “Continuous Read Mode” bits (M7-0) after the input 3-byte address (A23-A0). If the “Continuous Read Mode” bits (M5- 4) = (1, 0), then the next Quad I/O Fast Read command (after CS# is raised and then lowered) does not re-quire the EBH command code. The command sequence is shown in Figure 13. If the “Continuous Read Mode” (M5- 4) do not equal (1, 0), the next command requires the first EBH command code, thus returning to normal operation. A “Continuous Read Mode” Reset command can be used to reset (M5- 4) before issuing normal command.

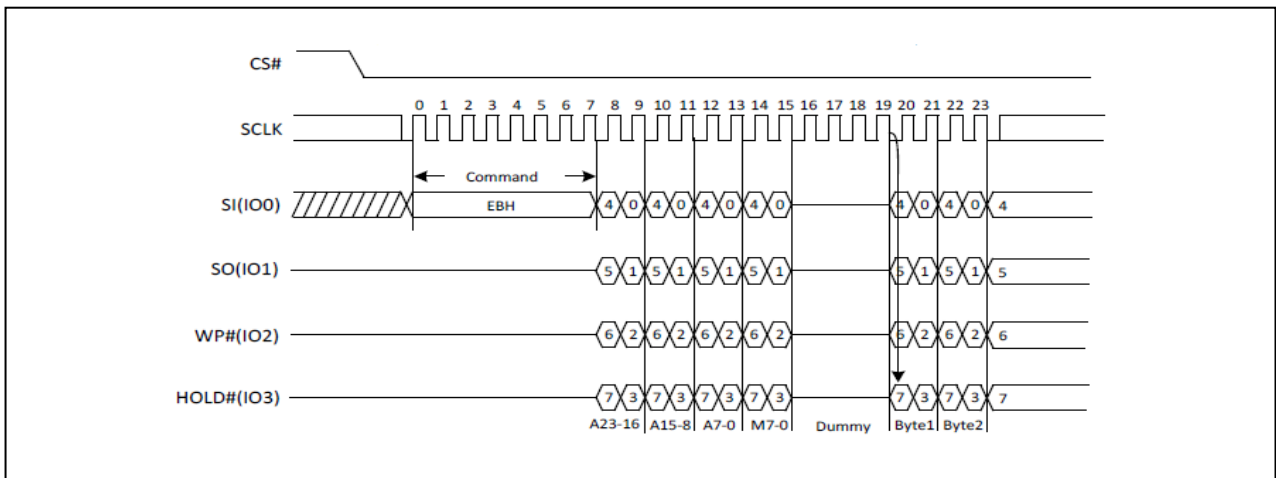


Figure12.Quad I/O Fast Read Sequence Diagram (M5-4≠ (1, 0))

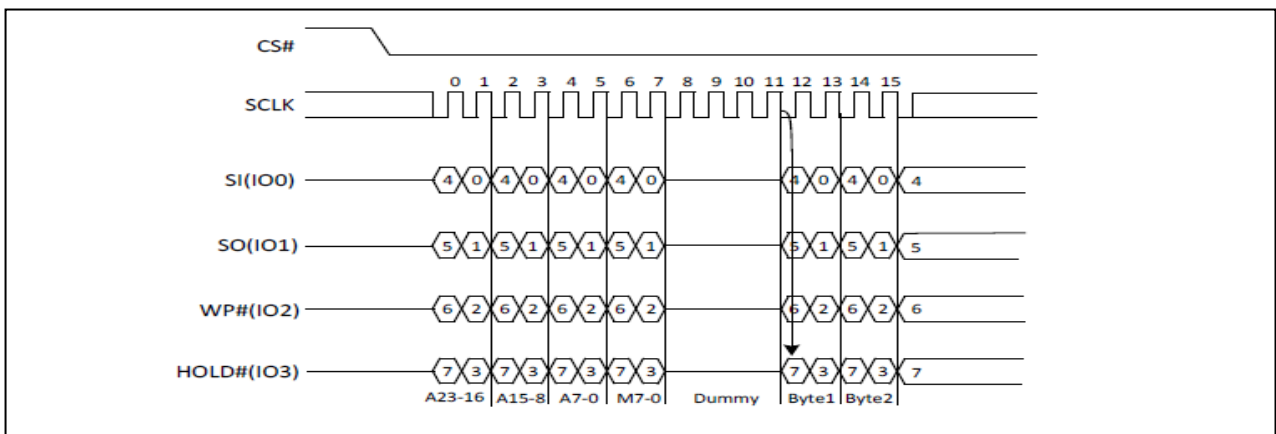


Figure13.Quad I/O Fast Read Sequence Diagram (M5-4= (1, 0))



Quad I/O Word Fast Read(E7H)

The Quad I/O Word Fast Read command is similar to the Quad I/O Fast Read command except that the lowest address bit (A0) must equal 0 and only 2-dummy clock. The command sequence is shown in followed Figure 14. The first byte addressed can be at any location. The address is automatically incremented to the next higher address after each byte of data is shifted out. The Quad Enable bit (QE) of Status Register (S9) must be set to enable for the Quad I/O Word Fast read command.

Quad I/O Word Fast Read with “Continuous Read Mode”

The Quad I/O Word Fast Read command can further reduce command overhead through setting the “Continuous Read Mode” bits (M7-0) after the input 3-byte address (A23-A0). If the “Continuous Read Mode” bits (M5- 4) = (1, 0), then the next Quad I/O Word Fast Read command (after CS# is raised and then lowered) does not require the E7H command code. The command sequence is shown in followed Figure 15. If the “Continuous Read Mode” bits (M5- 4) do not equal (1, 0), the next command requires the first E7H command code, thus returning to normal operation. A “Continuous Read Mode” Reset command can be used to reset (M7-0) before issuing normal command.

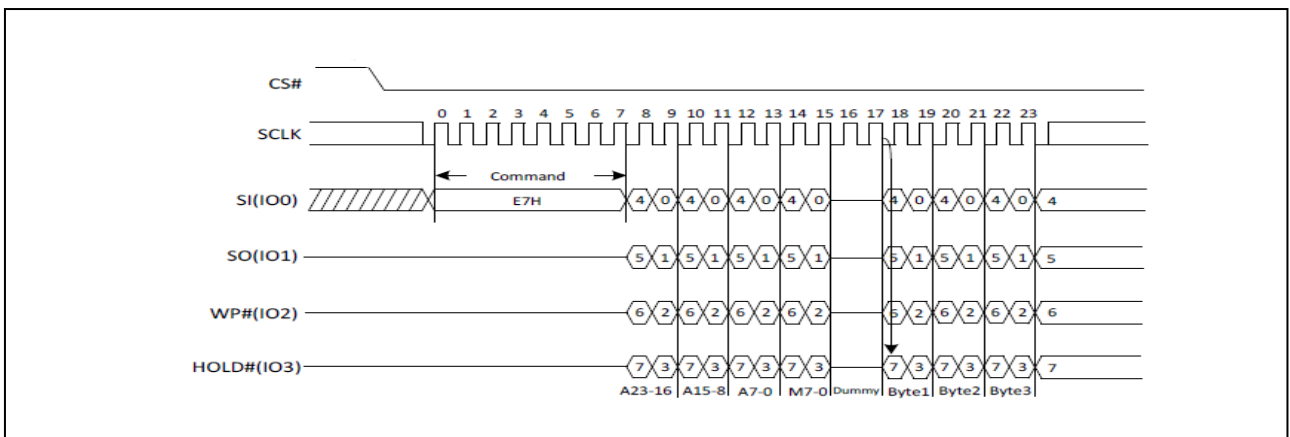


Figure14.Quad I/O Word Fast Read Sequence Diagram (M5-4≠ (1, 0))

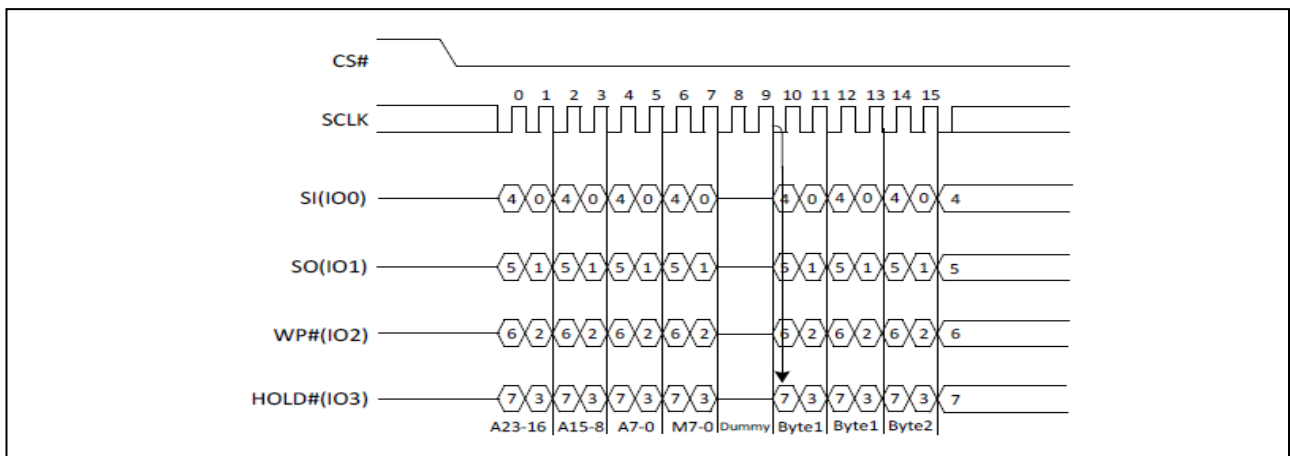


Figure15.Quad I/O Word Fast Read Sequence Diagram (M5-4= (1, 0))



Page Program (PP) (02H)

The Page Program (PP) command is for programming the memory. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit before sending the Page Program command.

The Page Program (PP) command is entered by driving CS# Low, followed by the command code, three address bytes and at least one data byte on SI. If the 8 least significant address bits (A7-A0) are not all zero, all transmitted data that goes beyond the end of the current page are programmed from the start address of the same page (from the address whose 8 least significant bits (A7-A0) are all zero). CS# must be driven low for the entire duration of the sequence. The Page Program command sequence: CS# goes low sending Page Program command 3-byte address on SI at least 1 byte data on SI CS# goes high. The command sequence is shown in Figure16. If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page. CS# must be driven high after the eighth bit of the last data byte has been latched in; otherwise the Page Program (PP) command is not executed.

As soon as CS# is driven high, the self-timed Page Program cycle (whose duration is t_{PP}) is initiated. While the Page Program cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Page Program cycle, and is 0 when it is completed. As some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset.

A Page Program (PP) command applied to a page which is protected by the Block Protect (BP3, BP2, BP1, BP0) is not executed.

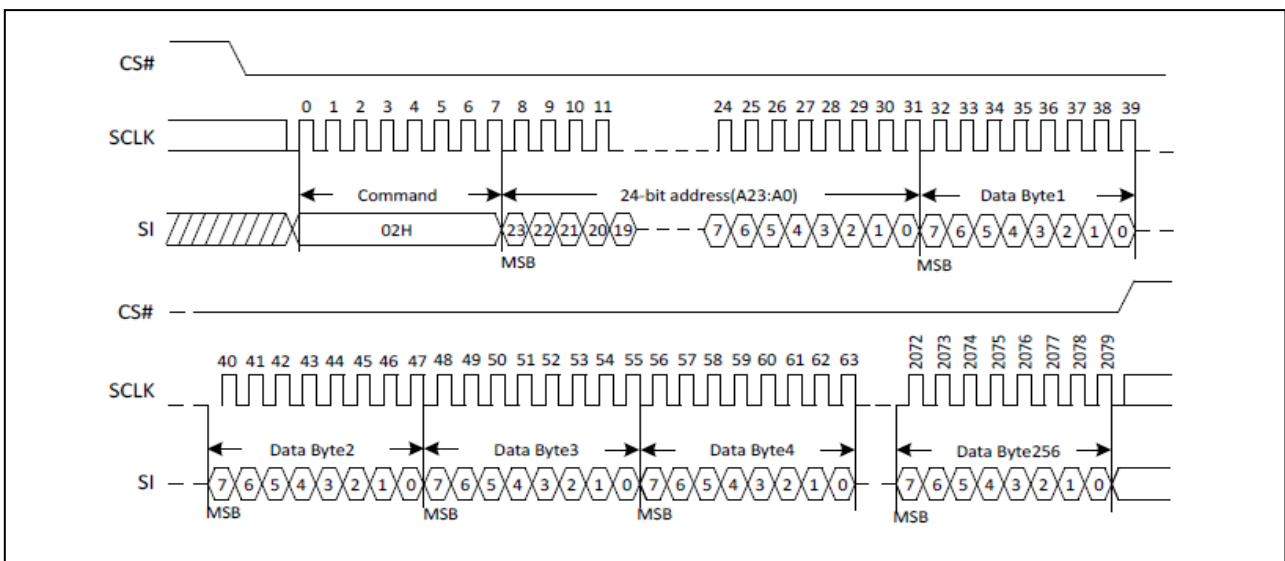


Figure16. Page Program Sequence Diagram



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Quad Page Program (QPP) (32H)

The Quad Page Program command is for programming the memory using four pins: IO0, IO1, IO2, and IO3. To use Quad Page Program the Quad enable in status register Bit9 must be set (QE=1). A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit before sending the Page Program command. The Quad Page Program command is entered by driving CS# Low, followed by the command code (32H), three address bytes and at least one data byte on IO pins.

The command sequence is shown in Figure 17. If more than 256 bytes are sent to the device, previously latched data are discarded and the last 256 data bytes are guaranteed to be programmed correctly within the same page. If less than 256 data bytes are sent to device, they are correctly programmed at the requested addresses without having any effects on the other bytes of the same page. CS# must be driven high after the eighth bit of the last data byte has been latched in; otherwise the Quad Page Program command is not executed.

As soon as CS# is driven high, the self-timed Quad Page Program cycle (whose duration is tPP) is initiated. While the Quad Page Program cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Quad Page Program cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset.

A Quad Page Program command applied to a page which is protected by the Block Protect (BP3, BP2, BP1, BP0) will not be executed.

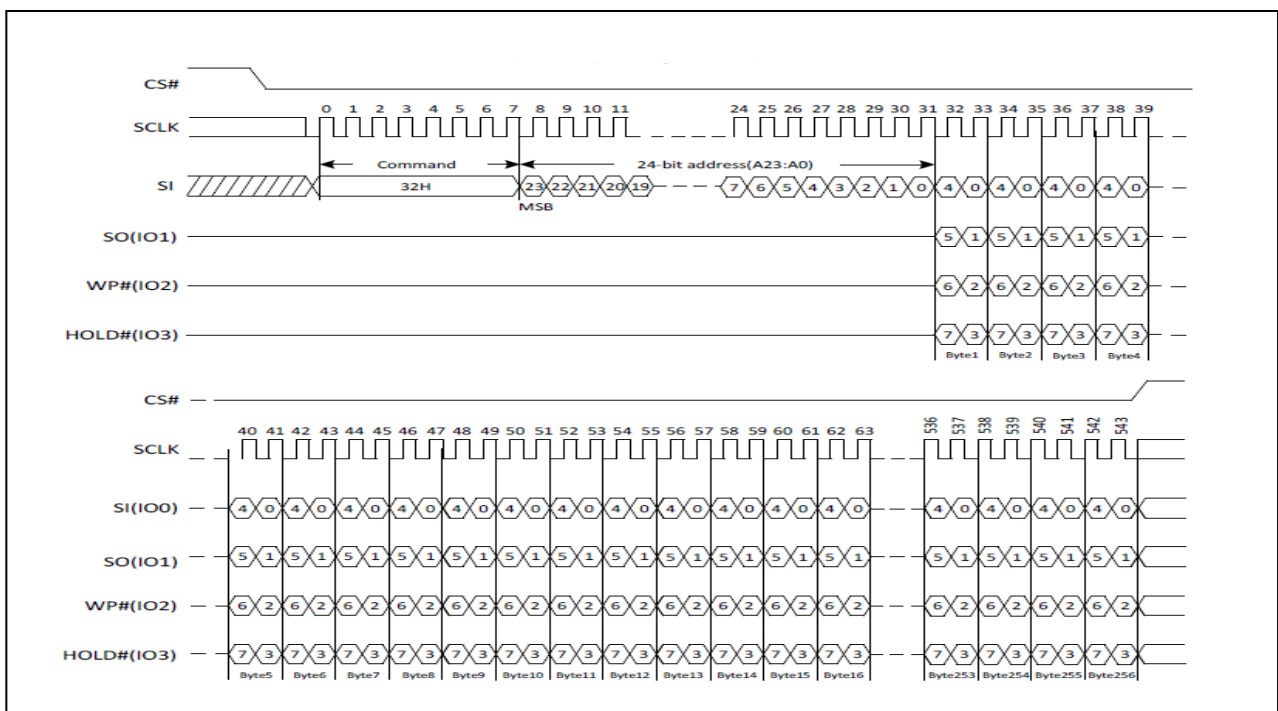


Figure17. Quad Page Program Sequence Diagram



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4 x I/O Page Program (4PP)

The Quad Page Program (4PP) instruction is for programming the memory to be "0". A Write Enable (WREN) instruction must execute to set the Write Enable Latch (WEL) bit and Quad Enable (QE) bit must be set to "1" before sending the Quad Page Program (4PP). The Quad Page Programming takes four pins: SIO0, SIO1, SIO2, and SIO3 as address and data input, which can improve programmer performance and the effectiveness of application. The 4PP operation frequency supports as fast as f4PP. The other function descriptions are as same as standard page program.

The sequence of issuing 4PP instruction is: CS# goes low → sending 4PP instruction code → 3-byte address on SIO[3:0] → at least 1-byte on data on SIO[3:0] → CS# goes high .

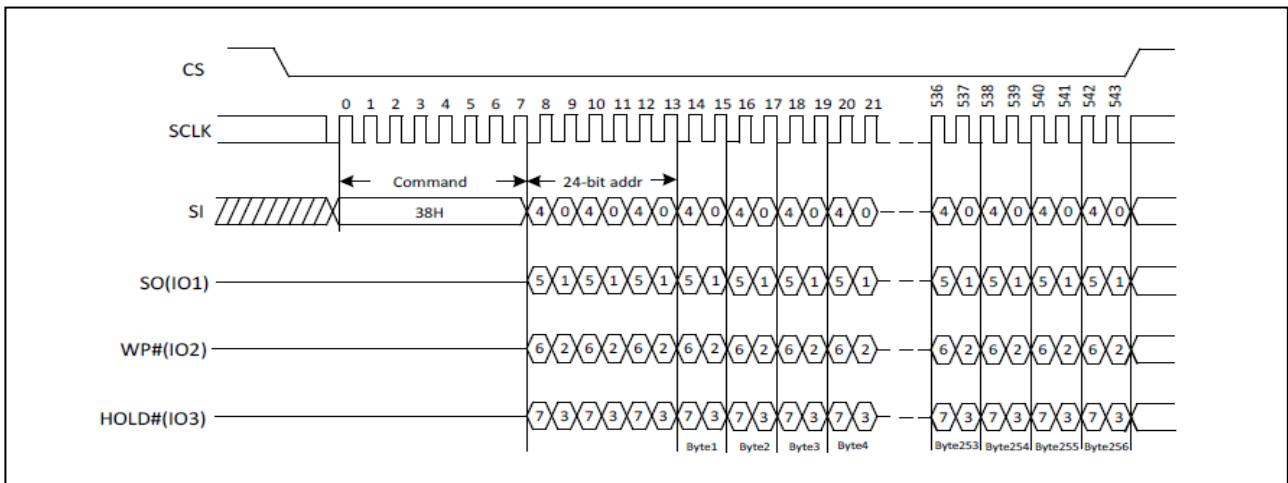


Figure18. Quad I/O Page Program Sequence Diagram

Sector Erase (SE) (20H)

The Sector Erase (SE) command is for erasing the all data of the chosen sector. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit. The Sector Erase (SE) command is entered by driving CS# low, followed by the command code, and 3-address byte on SI. Any address inside the sector is a valid address for the Sector Erase (SE) command. CS# must be driven low for the entire duration of the sequence.

The Sector Erase command sequence: CS# goes low sending Sector Erase command 3-byte address on SI CS# goes high. The command sequence is shown in Figure19. CS# must be driven high after the eighth bit of the last address byte has been latched in; otherwise the Sector Erase (SE) command is not executed. As soon as CS# is driven high, the self-timed Sector Erase cycle (whose duration is tSE) is initiated. While the Sector Erase cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Sector Erase cycle, and is 0 when it is completed.



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Write Enable Latch (WEL) bit is reset to 0 at the end of the Sector Erase cycle. Sector Erase (SE) command applied to a sector which is protected by the Block Protect (BP3,BP2, BP1, BP0) bit (see Table1 &1.1) will not be executed.

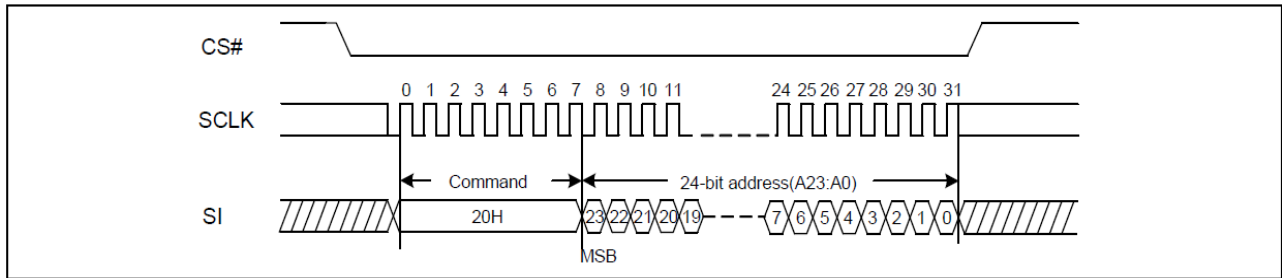


Figure19. Sector Erase Sequence Diagram

32KB Block Erase (BE) (52H)

The 32KB Block Erase (BE) command is for erasing the all data of the chosen block. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit. The 32KB Block Erase (BE) command is entered by driving CS# low, followed by the command code, and three address bytes on SI. Any address inside the block is a valid address for the 32KB Block Erase (BE) command. CS# must be driven low for the entire duration of the sequence.

The 32KB Block Erase command sequence: CS# goes low sending 32KB Block Erase command 3-byte address on SI, CS# goes high. The command sequence is shown in Figure20. CS# must be driven high after the eighth bit of the last address byte has been latched in; otherwise the 32KB Block Erase (BE) command is not executed. As soon as CS# is driven high, the self-timed Block Erase cycle (whose duration is tBE) is initiated. While the Block Erase cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Block Erase cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. A 32KB Block Erase (BE) command applied to a block which is protected by the Block Protect (BP3, BP2, BP1, BP0) bits (see Table1 & 1.1) will not be executed.

Note: Power disruption during erase operation will cause incomplete erase, thus recommend to perform a re-erase once power resume.

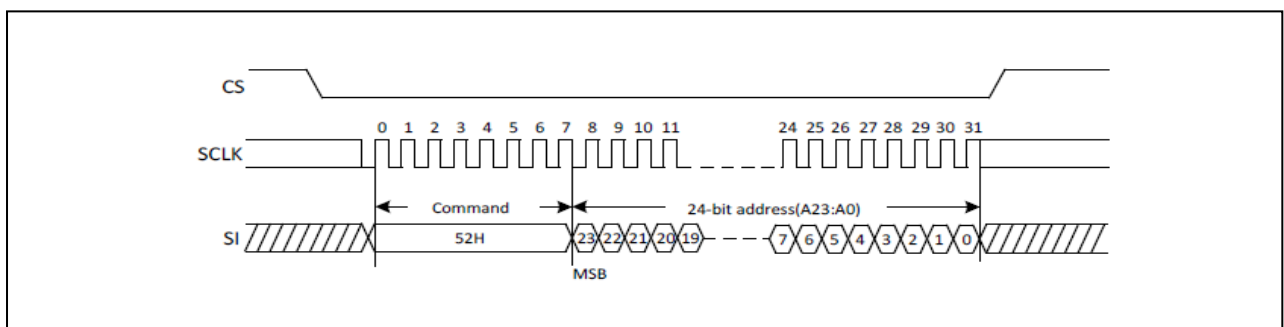


Figure20. 32KB Block Erase Sequence Diagram



64KB Block Erase (BE) (D8H)

The 64KB Block Erase (BE) command is for erasing the all data of the chosen block. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit. The 64KB Block Erase (BE) command is entered by driving CS# low, followed by the command code, and three address bytes on SI. Any address inside the block is a valid address for the 64KB Block Erase (BE) command. CS# must be driven low for the entire duration of the sequence.

The 64KB Block Erase command sequence: CS# goes low sending 64KB Block Erase command 3-byte address on SI, CS# goes high. The command sequence is shown in Figure21. CS# must be driven high after the eighth bit of the last address byte has been latched in; otherwise the 64KB Block Erase (BE) command is not executed. As soon as CS# is driven high, the self-timed Block Erase cycle (whose duration is tBE) is initiated. While the Block Erase cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Block Erase cycle, and is 0 when it is completed. Write Enable Latch (WEL) bit is reset t. A 64KB Block Erase (BE) commands applied to a block which is protected by the Block Protect (BP3,BP2, BP1, BP0) bits (see Table1 & 1.1) will not be executed.

Note: Power disruption during erase operation will cause incomplete erase, thus recommend to perform a re-erase once power resume.

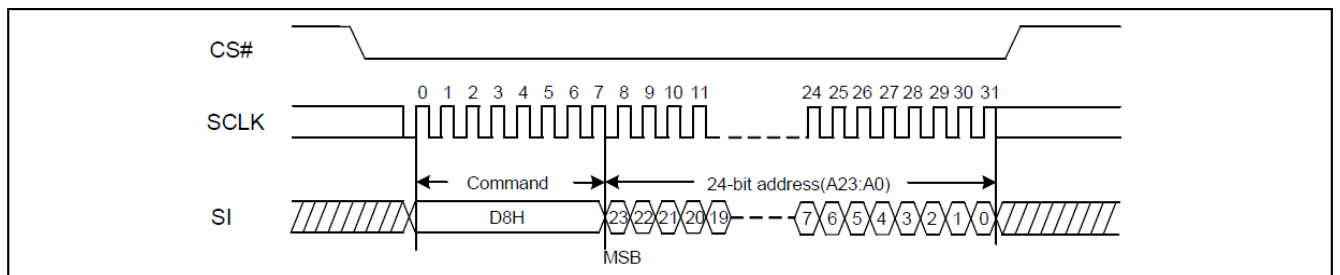


Figure21. 64KB Block Erase Sequence Diagram

Chip Erase (CE) (60/C7H)

The Chip Erase (CE) command is for erasing the all data of the chip. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit .The Chip Erase (CE) command is entered by driving CS# Low, followed by the command code on Serial Data Input (SI). CS# must be driven Low for the entire duration of the sequence.

The Chip Erase command sequence: CS# goes low send Chip Erase command CS# goes high. The command sequence is shown in Figure22. CS# must be driven high after the eighth bit of the command code has been latch in, otherwise the Chip Erase command is not executed. As soon as CS# is driven high, the self-timed Chip Erase cycle (whose duration is tCE) is initiated. While the Chip Erase cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Chip Erase cycle, and is 0 when it is completed.



At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. The Chip Erase (CE) command is executed if the Block protected by (BP3, BP2, BP1, BP0) bits. The Chip Erase(CE) command is ignored if one or more sectors are protected.

Note: Power disruption during erase operation will cause incomplete erase, thus recommend to perform a re-erase once power resume.

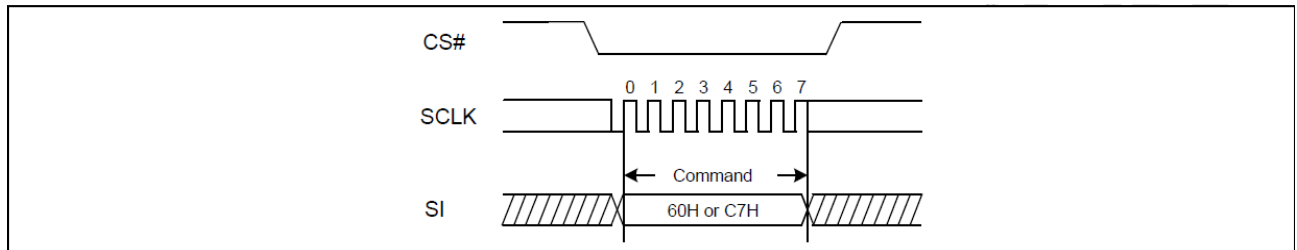


Figure22. Chip Erase Sequence Diagram

Deep Power-Down (DP) (B9H)

Executing the Deep Power-Down (DP) command is the only way to put the device in the lowest consumption mode (the Deep Power-Down Mode). It can also be used as an extra software protection mechanism, while the device is not in active use, since in this mode, the device ignores all Write, Program and Erase commands. Driving CS# high deselects the device, and puts the device in the Standby Mode (if there is no internal cycle currently in progress). But this mode is not the Deep Power-Down Mode. The Deep Power-Down Mode can only be entered by executing the Deep Power-Down (DP) command. Once the device has entered the Deep Power-Down Mode, all commands are ignored except the Release from Deep Power-Down and Read Device ID (RDI) command. This releases the device from this mode. The Release from Deep Power-Down and Read Device ID (RDI) command also allows the Device ID of the device to be output on SO.

The Deep Power-Down Mode automatically stops at Power-Down, and the device always Power-Up in the Standby Mode. The Deep Power-Down (DP) command is entered by driving CS# low, followed by the command code on SI. CS# must be driven low for the entire duration of the sequence.

The Deep Power-Down command sequence: CS# goes low, sending Deep Power-Down command, CS# goes high. The command sequence is shown in Figure 23. CS# must be driven high after the eighth bit of the command code has been latched in; otherwise the Deep Power-Down (DP) command is not executed. As soon as CS# is driven high, it requires a delay of t_{DP} before the supply current is reduced to ICC2 and the Deep Power-Down Mode is entered. Any Deep Power-Down (DP) command, while an Erase, Program or Write cycle is in progress, is rejected without having any effects on the cycle that is in progress.



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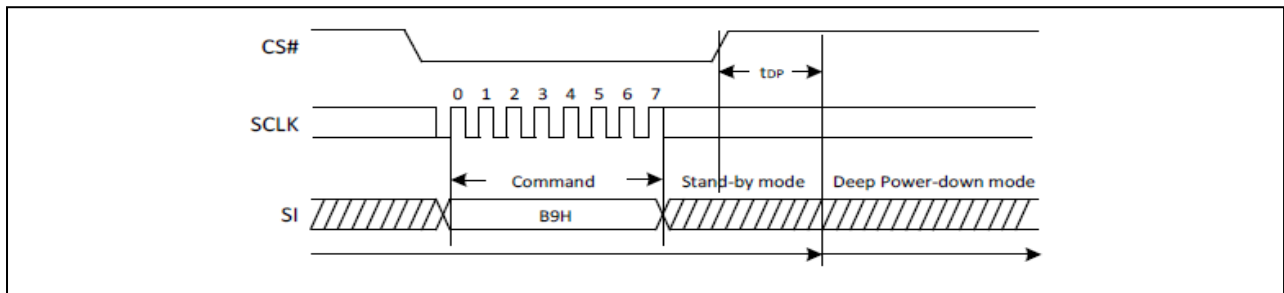


Figure23. Deep Power-Down Sequence Diagram

Release from Deep Power-Down and Read Device ID (RDI) (ABH)

The Release from Power-Down and Read/Device ID command is a multi-purpose command. It can be used to release the device from the Power-Down state or obtain the devices electronic identification (ID) number. To release the device from the Power-Down state, the command is issued by driving the CS# pin low, shifting the instruction code “ABH” and driving CS# high as shown in Figure24. Release from Power-Down will take the time duration of tRES1 (See AC Characteristics) before the device will resume normal operation and other command are accepted. The CS# pin must remain high during the tRES1 time duration.

When used only to obtain the Device ID while not in the Power-Down state, the command is initiated by driving the CS# pin low and shifting the instruction code “ABH” followed by 3-dummy byte. The Device ID bits are then shifted out on the falling edge of SCLK with most significant bit (MSB) first as shown in Figure25. The Device ID value for the ACE25AA400G is listed in Manufacturer and Device Identification table. The Device ID can be read continuously. The command is completed by driving CS# high.

When used to release the device from the Power-Down state and obtain the Device ID, the command is the same as previously described, and shown in Figure 25, except that after CS# is driven high it must remain high for a time duration of tRES2 (See AC Characteristics). After this time duration the device will resume normal operation and other command will be accepted. If the Release from Power-Down/Device ID command is issued while an Erase, Program or Write cycle is in process (when WIP equal 1) the command is ignored and will not affects on the current cycle.

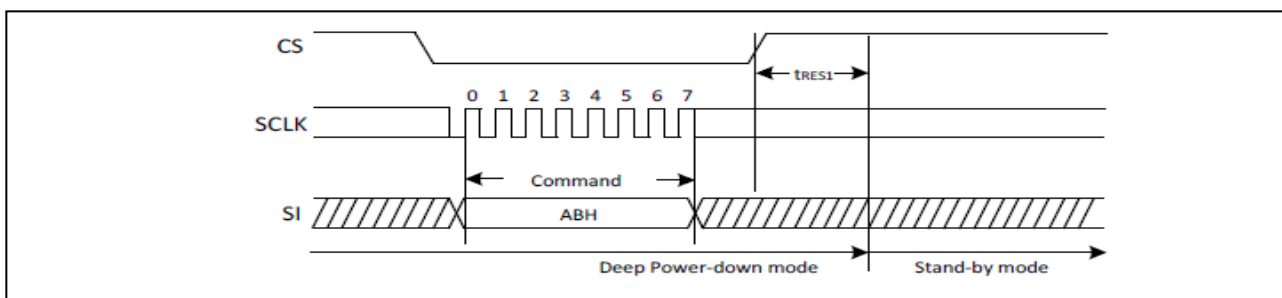


Figure24. Release Power-Down Sequence Diagram



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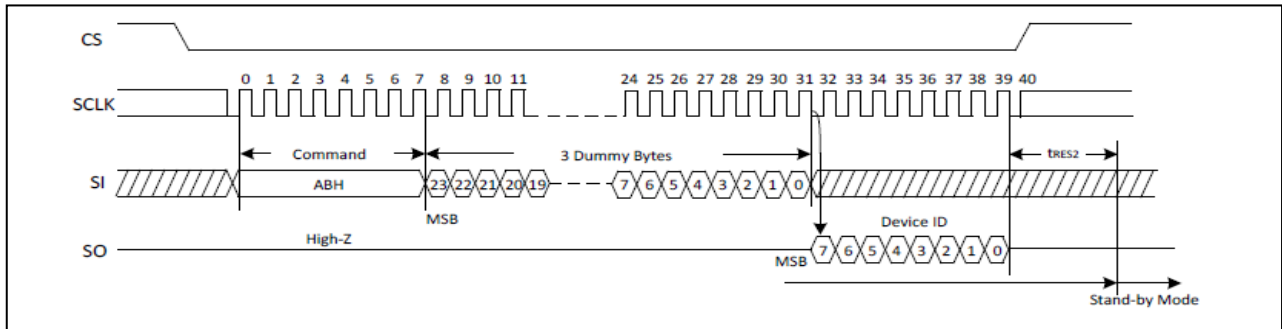


Figure 25. Release Power-Down / Read Device ID Sequence Diagram

Read Manufacturer ID/ Device ID (REMS) (90H)

The Read Manufacturer/Device ID command is an alternative to the Release from Power-Down / Device ID command that provides both the JEDEC assigned Manufacturer ID and the specific Device ID. The command is initiated by driving the CS# pin low and shifting the command code “90H” followed by a 24-bit address (A23-A0) of 000000H. After which, the Manufacturer ID and the Device ID are shifted out on the falling edge of SCLK with most significant bit (MSB) first is shown in Figure 26. If the 24-bit address is initially set to 000001H, the Device ID will be read first.

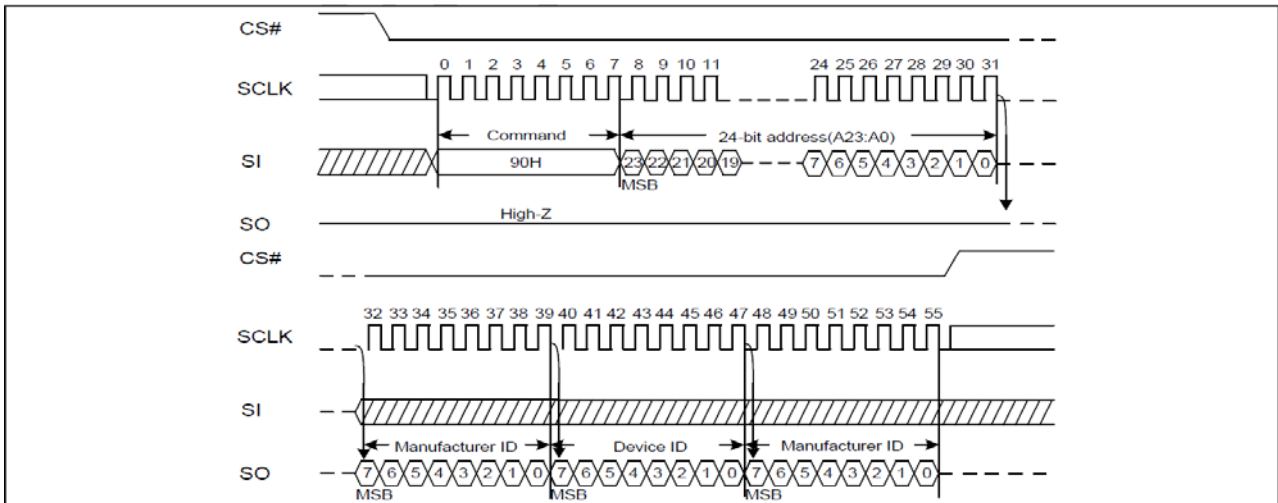


Figure 26. Read ID Sequence Diagram

Continuous Read Mode Reset (CRMR) (FFH)

The Dual/Quad I/O Fast Read operations, “Continuous Read Mode” bits (M7-0) are implemented to further reduce command overhead. By setting the (M7-0) to AXH, the next Dual/Quad I/O Fast Read operations do not require the BBH/EBH/E7H command code.

Because the ACE25AA400G has no hardware reset pin, so if Continuous Read Mode bits are set to “AXH”, the ACE25AA400G will not recognize any standard SPI commands. So Continuous Read Mode Reset command will release the Continuous Read Mode from the “AXH” state and allow standard SPI command to be recognized. The command sequence is shown in Figure 27.



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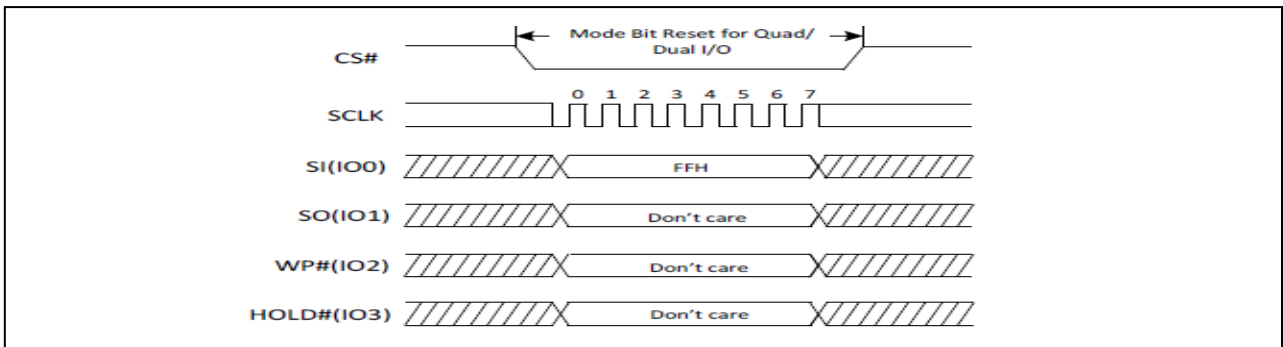


Figure 27. Continuous Read Mode Reset Sequence Diagram

Read Manufacturer ID/ Device ID Dual I/O (92H)

The Read Manufacturer/Device ID Dual I/O command is an alternative to the Release from Power-Down / Device ID command that provides both the JEDEC assigned Manufacturer ID and the specific Device ID by dual I/O.

The command is initiated by driving the CS# pin low and shifting the command code “92H” followed by a 24-bit address (A23-A0) of 000000H. After which, the Manufacturer ID and the Device ID are shifted out on the falling edge of SCLK with most significant bit (MSB) first as shown in Figure 27.1 If the 24-bit address is initially set to 000001H, the Device ID will be read first.

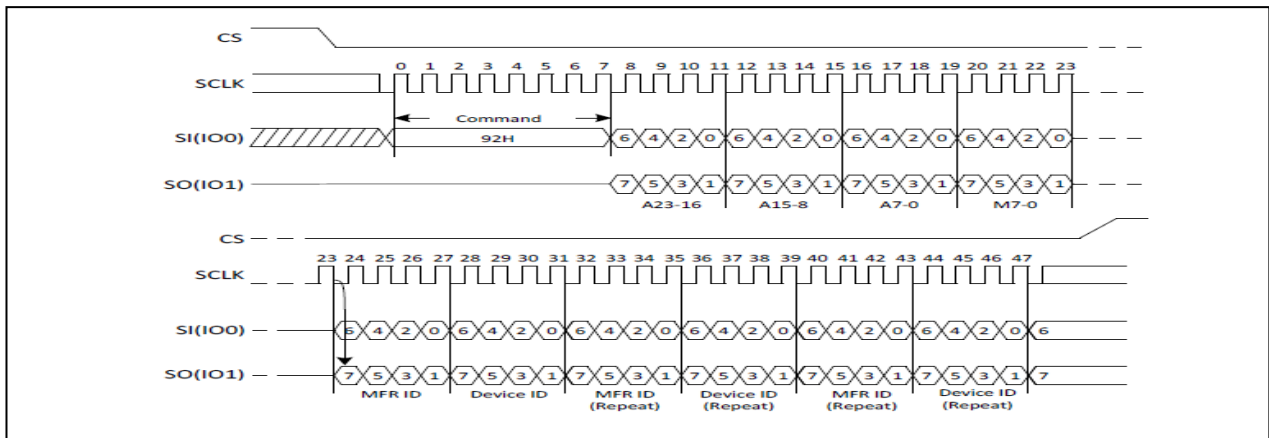


Figure 27.1 Read Manufacturer ID/ Device ID Dual I/O Sequence Diagram

Read Manufacturer ID/ Device ID Quad I/O (94H)

The Read Manufacturer/Device ID Quad I/O command is an alternative to the Release from Power-Down / Device ID command that provides both the JEDEC assigned Manufacturer ID and the specific Device ID by quad I/O. The command is initiated by driving the CS# pin low and shifting the command code “94H” followed by a 24-bit address (A23-A0) of 000000H. After which, the Manufacturer ID and the Device ID are shifted out on the falling edge of SCLK with most significant bit (MSB) first is shown in Figure 28. If the 24-bit address is initially set to 000001H, the Device ID will be read first.



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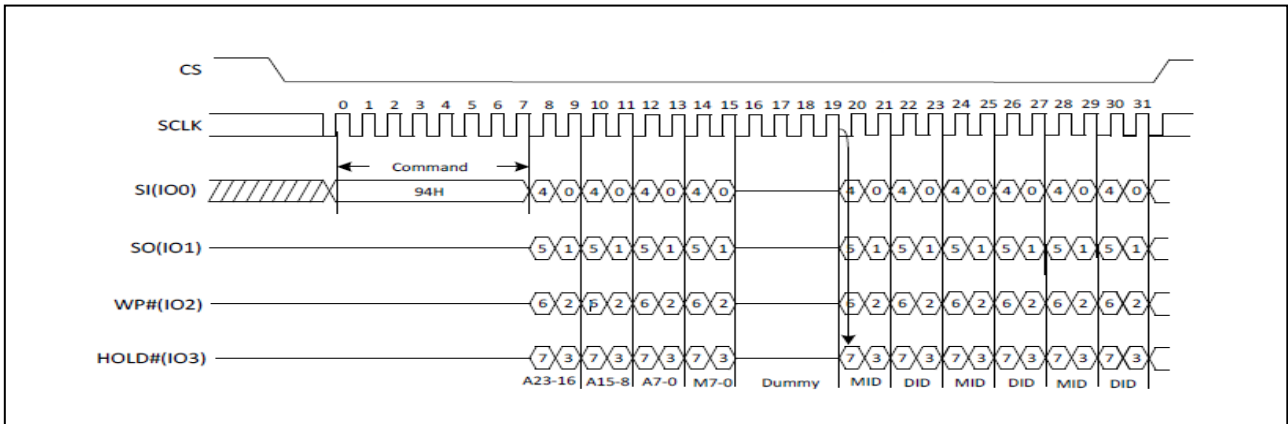


Figure 28. Read Manufacture ID/ Device ID Dual I/O Sequence Diagram

Read Identification (RDID) (9FH)

The Read Identification (RDID) command allows the 8-bit manufacturer identification to be read, followed by two bytes of device identification. The device identification indicates the memory type in the first byte, and the memory capacity of the device in the second byte. Any Read Identification (RDID) command while an Erase or Program cycle is in progress, is not decoded, and has no effect on the cycle that is in progress. The Read identification (RDID) command should not be issued while the device is in Deep Power-Down Mode.

The device is first selected by driving CS# to low. Then, the 8-bit command code for the command is shifted in. This is followed by the 24-bit device identification, stored in the memory, being shifted out on Serial Data Output, each bit being shifted out during the falling edge of Serial Clock. The command sequence is shown in Figure 29. The Read Identification (RDID) command is terminated by driving CS# to high at any time during data output. When CS# is driven high, the device is put in the Standby Mode. Once in the Standby Mode, the device waits to be selected, so that it can receive, decode and execute commands.

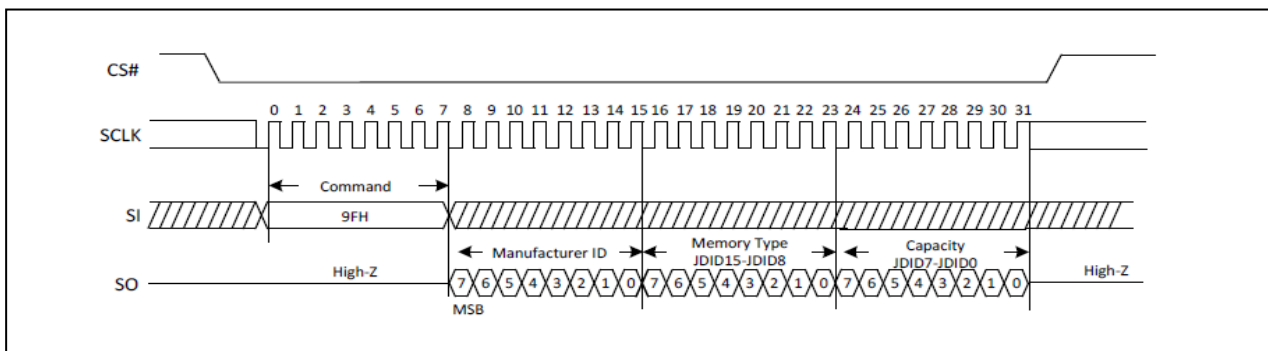


Figure 29. Read Identification ID Sequence Diagram



Erase Security Registers (44H)

The ACE25AA400G provides four 256-byte Security Registers which only erased all at once but able to program individually. These registers may be used by the system manufacturers to store security and other important information separately from the main memory array.

The Erase Security Registers command is similar to Sector/Block Erase command. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit.

The Erase Security Registers command sequence: CS# goes low, sending Erase Security Registers Command, CS# goes high. The command sequence is shown in Figure 30. CS# must be driven high after the eighth bit of the command code has been latched in, otherwise the Erase Security Registers command is not executed. As soon as CS# is driven high, the self-timed Erase Security Registers cycle (whose duration is tSE) is initiated. While the Erase Security Registers cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Erase Security Registers cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset. The Security Registers Lock Bit (LB) in the Status Register can be used to OTP protect the security registers. Once the LB bit is set to 1, the Security Registers will be permanently locked; the Erase Security Registers command will be ignored.

| Address | A23-A16 | A15-A10 | A9-A0 |
|--------------------|----------|---------|------------|
| Security Registers | 00000000 | 000000 | Don't Care |

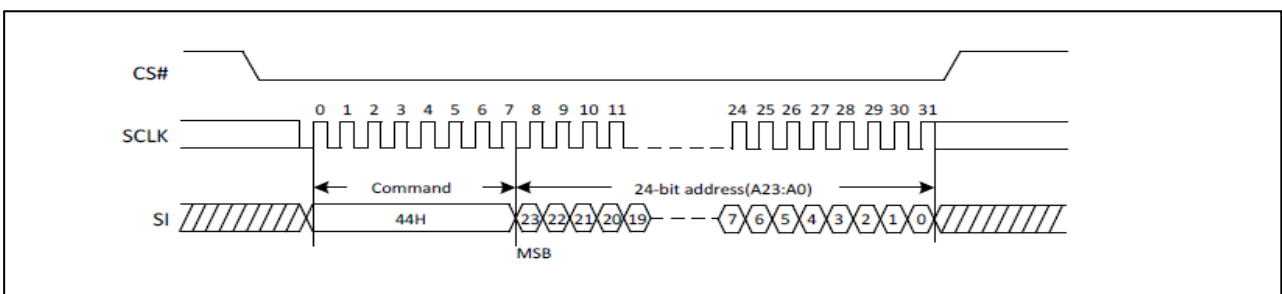


Figure30. Erase Security Registers command Sequence Diagram



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Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Program Security Registers (42H)

The Program Security Registers command is similar to the Page Program command. It allows from 1 to 256 bytes Security Registers data to be programmed. A Write Enable (WREN) command must previously have been executed to set the Write Enable Latch (WEL) bit before sending the Program Security Registers command. The Program Security Registers command is entered by driving CS# Low, followed by the command code (42H), three address bytes and at least one data byte on SI. As soon as CS# is driven high, the self-timed Program Security Registers cycle (whose duration is tPP) is initiated. While the Program Security Registers cycle is in progress, the Status Register may be read to check the value of the Write In Progress (WIP) bit. The Write In Progress (WIP) bit is 1 during the self-timed Program Security Registers cycle, and is 0 when it is completed. At some unspecified time before the cycle is completed, the Write Enable Latch (WEL) bit is reset.

If the Security Registers Lock Bit (LB) is set to 1, the Security Registers will be permanently locked. Program Security Registers command will be ignored.

| Address | A23-A16 | A15-A8 | A7-A0 |
|--------------------|---------|--------|--------------|
| Security Register0 | 00H | 00H | Byte Address |
| Security Register1 | 00H | 01H | Byte Address |
| Security Register2 | 00H | 02H | Byte Address |
| Security Register3 | 00H | 03H | Byte Address |

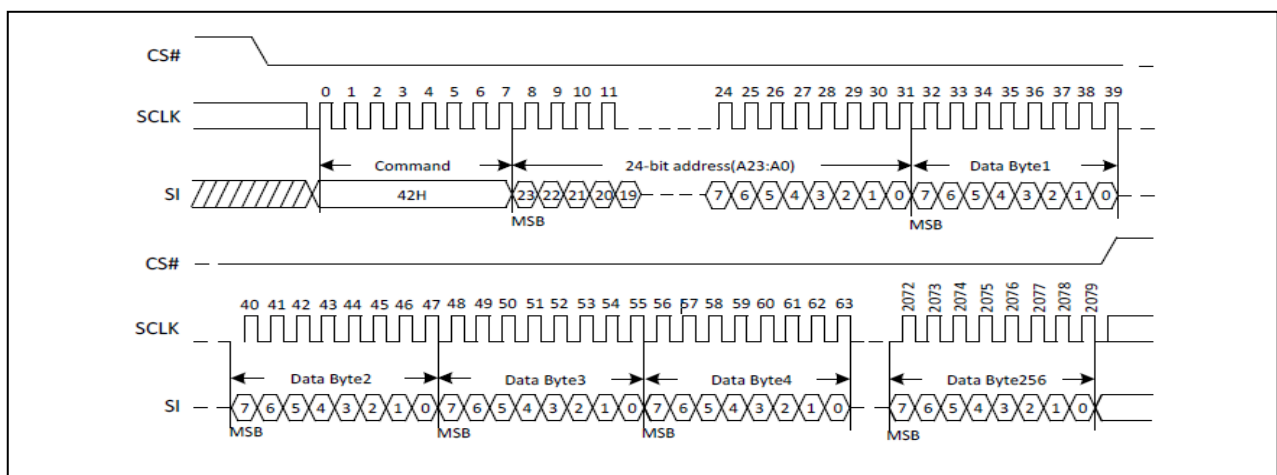


Figure31. Program Security Registers command Sequence Diagram



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Read Security Registers (48H)

The Read Security Registers command is similar to Fast Read command. The command is followed by a 3- byte address (A23-A0) and a dummy byte, each bit being latched-in during the rising edge of SCLK. Then the memory content, at that address, is shifted out on SO, each bit being shifted out, at a Max frequency fC, during the falling edge of SCLK. The first byte addressed can be at any location. The address is automatically increment- ed to the next address after each byte of data is shifted out. Once the A9-A0 address reaches the last byte of the register (Byte 3FFH), it will reset to 000H, the command is completed by driving CS# high.

| Address | A23-A16 | A15-A10 | A9-A0 |
|-------------------|----------|---------|---------|
| Security Register | 00000000 | 000000 | Address |

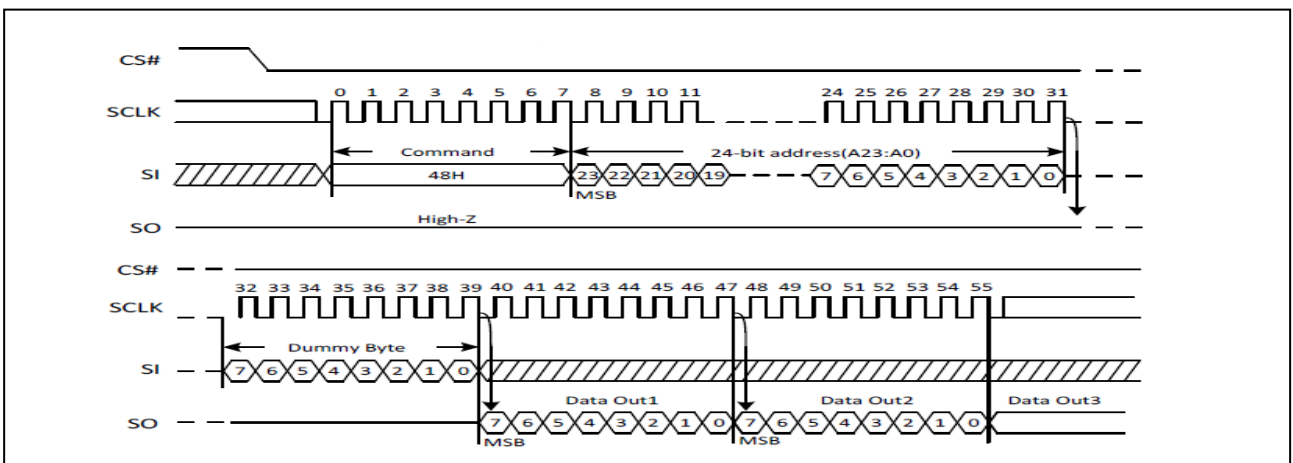


Figure 32. Read Security Registers command Sequence Diagram

Enable Reset (66H) and Reset (99H)

If the Reset command is accepted, any on-going internal operation will be terminated and the device will return to its default power-on state and lose all the current volatile settings, such as Volatile Status Register bits, Write Enable Latch status (WEL), Program/Erase Suspend status, Read Parameter setting (P7-P0) and Wrap Bit Setting (W6-W4).

The “Reset (99H)” command sequence as follow: CS# goes low Sending Enable Reset command CS# goes high CS# goes low Sending Reset command CS# goes high. Once the Reset command is accepted by the device, the device will take approximately tRSTR to reset. During this period, no command will be accepted. Data corruption may happy if there is an on-going or suspended internal Erase or Program operation when Reset command sequence is accepted by the device. It is recommended to check the BUSY bit in Status Register before issuing the Reset command sequence.



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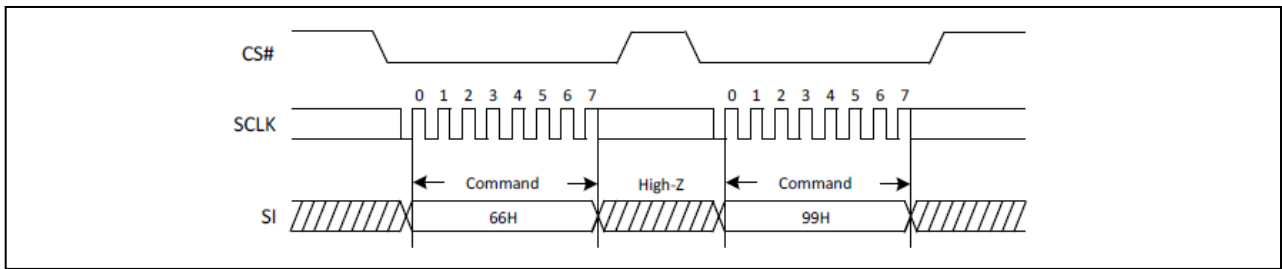


Figure33. Enable Reset and Reset command Sequence Diagram

Read Serial Flash Discoverable Parameter (5AH)

The Serial Flash Discoverable Parameter (SFDP) standard provides a consistent method of describing the functional and feature capabilities of serial flash devices in a standard set of internal parameter tables. These parameter tables can be interrogated by host system software to enable adjustments needed to accommodate divergent features from multiple vendors. The concept is similar to the one found in the Introduction of JEDEC Standard, JESD68 on CFI. SFDP is a standard of JEDEC Standard No.216.

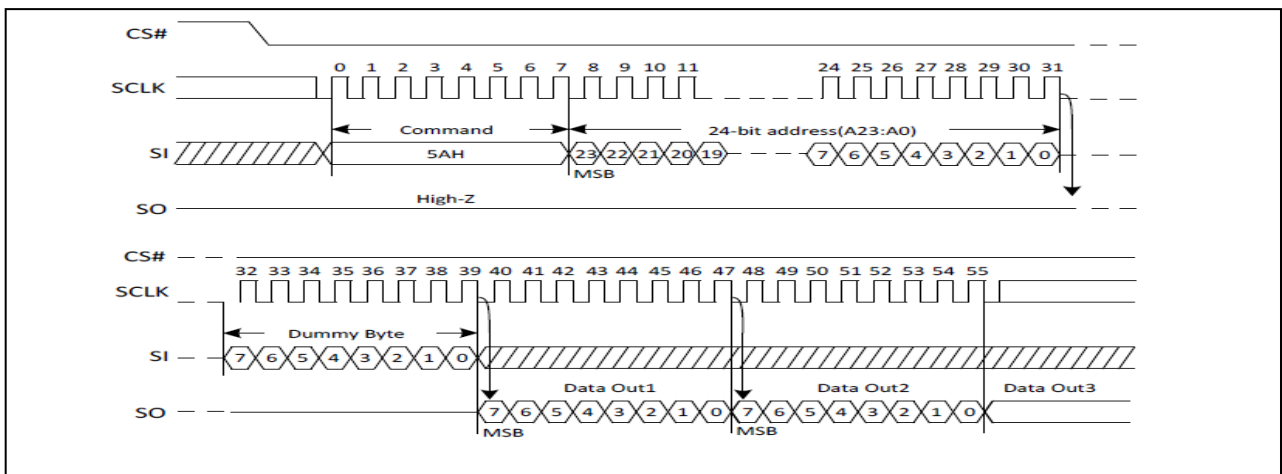


Figure34. Read Serial Flash Discoverable Parameter command Sequence Diagram



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Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Read Unique ID (RUID)

The Read Unique ID command accesses a factory-set read-only 128bit number that is unique to each ACE25AA400G device. The Unique ID can be used in conjunction with user software methods to help prevent copy- ing or cloning of a system.

The Read Unique ID command sequence: CS# goes low → sending Read Unique ID command →00H →01H→94H→ Dummy byte 128bit Unique ID Out → CS# goes high.

The command sequence is show below.

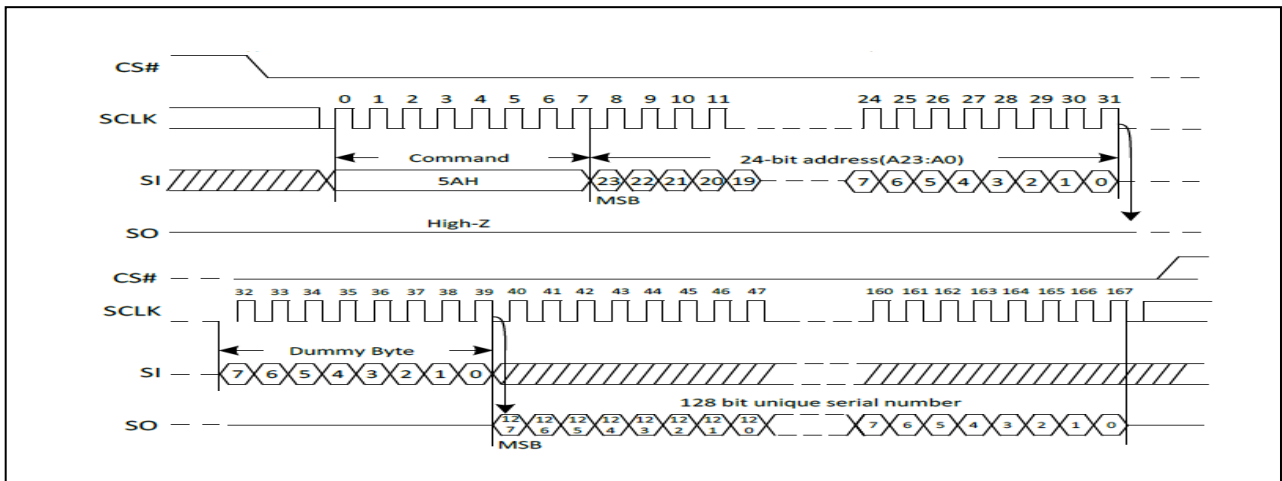


Figure34.1 Read Unique ID (RUID) Sequence (Command 5AH)



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Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Table 3. Signature and Parameter Identification Data Values

| Description | Comment | Add(H) (Byte) | DW Add (Bit) | Data | Data |
|---|--|------------------|-----------------|------|------|
| SFDP Signature | Fixed:50444653H | 00H | 07:00 | 53H | 53H |
| | | 01H | 15:08 | 46H | 46H |
| | | 02H | 23:16 | 44H | 44H |
| | | 03H | 31:24 | 50H | 50H |
| SFDP Minor Revision Number | Start from 00H | 04H | 07:00 | 00H | 00H |
| SFDP Major Revision Number | Start from 01H | 05H | 15:08 | 01H | 01H |
| Number of Parameters Headers | Start from 00H | 06H | 23:16 | 01H | 01H |
| Unused | Contains 0xFFH and can never be changed | 07H | 31:24 | FFH | FFH |
| ID number (JEDEC) | 00H: It indicates a JEDEC specified header | 08H | 07:00 | 00H | 00H |
| Parameter Table Minor Revision Number | Start from 0x00H | 09H | 15:08 | 00H | 00H |
| Parameter Table Major Revision Number | Start from 0x01H | 0AH | 23:16 | 01H | 01H |
| Parameter Table Length (in double word) | How many DWORDs in the Parameter table | 0BH | 31:24 | 09H | 09H |
| Parameter Table Pointer (PTP) | First address of JEDEC Flash Parameter table | 0CH | 07:00 | 30H | 30H |
| | | 0DH | 15:08 | 00H | 00H |
| | | 0EH | 23:16 | 00H | 00H |
| Unused | Contains 0xFFH and can never be changed | 0FH | 31:24 | FFH | FFH |
| ID Number(ACE Manufacturer ID) | It is indicates ACE manufacturer ID | 10H | 07:00 | 0BH | 0BH |
| Parameter Table Minor Revision Number | Start from 0x00H | 11H | 15:08 | 00H | 00H |
| Parameter Table Major Revision Number | Start from 0x01H | 12H | 23:16 | 01H | 01H |
| Parameter Table Length (in double word) | How many DWORDs in the Parameter table | 13H | 31:24 | 03H | 03H |
| Parameter Table Pointer (PTP) | First address of Flash Parameter table | 14H | 07:00 | 60H | 60H |
| | | 15H | 15:08 | 00H | 00H |
| | | 16H | 23:16 | 00H | 00H |
| Unused | Contains 0xFFH and can never be changed | 17H | 31:24 | FFH | FFH |



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Table 4. Parameter Table (0): JEDEC Flash Parameter Tables

| Description | Comment | Add(H) (Byte) | DW Add (Bit) | Data | Data |
|---|---|------------------|-----------------|------------|------|
| Block/Sector Erase Size | 00: Reserved; 01: 4KB erase; 10: Reserved; 11: not support 4KB erase | 30H | 01:00 | 01b | E5H |
| Write Granularity | 0: 1Byte, 1: 64Byte or larger | | 02 | 1b | |
| Write Enable Instruction Requested for Writing to Volatile Status Registers | 0: Nonvolatile status bit 1: Volatile status bit (BP status register bit) | | 03 | 0b | |
| Write Enable Opcode Select for Writing to Volatile Status Registers | 0: Use 50H Opcode, 1: Use 06H Opcode, Note: If target flash status register is Nonvolatile, then bits 3 and 4 must be set to 00b. | | 04 | 0b | |
| Unused | Contains 111b and can never be changed | | 07:05 | 111b | |
| 4KB Erase Opcode | | 31H | 15:08 | 20H | 20H |
| (1-1-2) Fast Read | 0=Not support, 1=Support | 32H | 16 | 1b | F1H |
| Address Bytes Number used in addressing flash array | 00: 3Byte only, 01: 3 or 4Byte, 10: 4Byte only, 11: Reserved | | 18:17 | 00b | |
| Double Transfer Rate (DTR) clocking | 0=Not support, 1=Support | | 19 | 0b | |
| (1-2-2) Fast Read | 0=Not support, 1=Support | | 20 | 1b | |
| (1-4-4) Fast Read | 0=Not support, 1=Support | | 21 | 1b | |
| (1-1-4) Fast Read | 0=Not support, 1=Support | | 22 | 1b | |
| Unused | | | 23 | 1b | |
| Unused | | | 33H | 31:24 | |
| Flash Memory Density | | 37H:34H | 31:00 | 007FFFFFFH | |



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| | | | | | |
|---|---|---------|-------|--------|-------|
| (1-4-4) Fast Read Number of Wait states | 0 0000b: Wait states (Dummy Clocks) not support | 38H | 04:00 | 00100b | 44H |
| (1-4-4) Fast Read Number of Mode Bits | 000b: Mode Bits not support | | 07:05 | 010b | |
| (1-4-4) Fast Read Opcode | | 39H | 15:08 | EBH | EBH |
| (1-1-4) Fast Read Number of Wait states | 0 0000b: Wait states (Dummy Clocks) not support | 3AH | 20:16 | 01000b | 08H |
| (1-1-4) Fast Read Number of Mode Bits | 000b: Mode Bits not support | | 23:21 | 000b | |
| (1-1-4) Fast Read Opcode | | 3BH | 31:24 | 6BH | 6BH |
| (1-1-2) Fast Read Number of Wait states | 0 0000b: Wait states (Dummy Clocks) not support | 3CH | 04:00 | 01000b | 08H |
| (1-1-2) Fast Read Number of Mode Bits | 000b: Mode Bits not support | | 07:05 | 000b | |
| (1-1-2) Fast Read Opcode | | 3DH | 15:08 | 3BH | 3BH |
| (1-2-2) Fast Read Number of Wait states | | 3EH | 20:16 | 00010b | 42H |
| (1-2-2) Fast Read Number of Mode Bits | | | 23:21 | 010b | |
| (1-2-2) Fast Read Opcode | | 3FH | 31:24 | BBH | BBH |
| (2-2-2) Fast Read | 0=not support 1=support | 40H | 00 | 0b | EEH |
| Unused | | | 03:01 | 111b | |
| (4-4-4) Fast Read | 0=not support 1=support | | 04 | 0b | |
| Unused | | | 07:05 | 111b | |
| Unused | | 43H:41H | 31:08 | 0xFFH | 0xFFH |
| Unused | | 45H:44H | 15:00 | 0xFFH | 0xFFH |
| (2-2-2) Fast Read Number of Wait states | 0 0000b: Wait states (Dummy Clocks) not support | 46H | 20:16 | 00000b | 00H |
| (2-2-2) Fast Read Number of Mode Bits | 000b: Mode Bits not support | | 23:21 | 000b | |
| (2-2-2) Fast Read Opcode | | 47H | 31:24 | FFH | FFH |
| Unused | | 49H:48H | 15:00 | 0xFFH | 0xFFH |



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Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

| | | | | | |
|---|---|-----|-------|--------|-----|
| (4-4-4) Fast Read Number of Wait states | 0 0000b: Wait states (Dummy Clocks) not support | 4AH | 20:16 | 00000b | 00H |
| (4-4-4) Fast Read Number of Mode Bits | 000b: Mode Bits not support | | 23:21 | 000b | |
| (4-4-4) Fast Read Opcode | | 4BH | 31:24 | FFH | FFH |
| Sector Type 1 Size | Sector/block size= 2^N bytes 0x00b: this sector type don't exist | 4CH | 07:00 | 0CH | 0CH |
| Sector Type 1 erase Opcode | | 4DH | 15:08 | 20H | 20H |
| Sector Type 2 Size | Sector/block size= 2^N bytes 0x00b: this sector type don't exist | 4EH | 23:16 | 0FH | 0FH |
| Sector Type 2 erase Opcode | | 4FH | 31:24 | 52H | 52H |
| Sector Type 3 Size | Sector/block size= 2^N bytes 0x00b: this sector type don't exist | 50H | 07:00 | 10H | 10H |
| Sector Type 3 erase Opcode | | 51H | 15:08 | D8H | D8H |
| Sector Type 4 Size | Sector/block size= 2^N bytes 0x00b: this sector type don't exist | 52H | 23:16 | 00H | 00H |
| Sector Type 4 erase Opcode | | 53H | 31:24 | FFH | FFH |



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Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Table 5. Parameter Table (1): ACE Flash Parameter Tables

| Description | Comment | Add(H) (Byte) | DW Add (Bit) | Data | Data |
|---|---|------------------|-----------------|-------|-------|
| Vcc Supply Maximum Voltage | 2000H=2.000V 2700H=2.700V 3600H=3.600V | 61H:60H | 15:00 | 3600H | 3600H |
| Vcc Supply Minimum Voltage | 1650H=1.650V 2250H=2.250V 2300H=2.300V 2700H=2.700V | 63H:62H | 31:16 | 2700H | 2700H |
| HW Reset# pin | 0=not support 1=support | 65H:64H | 00 | 0b | 7994H |
| HW Hold# pin | 0=not support 1=support | | 01 | 0b | |
| Deep Power Down Mode | 0=not support 1=support | | 02 | 1b | |
| SW Reset | 0=not support 1=support | | 03 | 0b | |
| SW Reset Opcode | Should be issue Reset Enable(66H) before Reset cmd | | 11:04 | 99H | |
| Program Suspend/Resume | 0=not support 1=support | | 12 | 1b | |
| Erase Suspend/Resume | 0=not support 1=support | | 13 | 1b | |
| Unused | | | 14 | 1b | |
| Wrap-Around Read mode | 0=not support 1=support | | 15 | 0b | |
| Wrap-Around Read mode Opcode | | 66H | 23:16 | FFH | FFH |
| Wrap-Around Read data length | 08H:support 8B wrap-around read 16H:8B&16B 32H:8B&16B&32B 64H:8B&16B&32B&64B | 67H | 31:24 | 64H | 64H |
| Individual block lock | 0=not support 1=support | 6BH:68H | 00 | 0b | E3FCH |
| Individual block lock bit (Volatile/Nonvolatile) | 0=Volatile 1=Nonvolatile | | 01 | 0b | |
| Individual block lock Opcode | | | 09:02 | FFH | |
| Individual block lock Volatile protect bit default protect status | 0=protect 1=unprotect | | 10 | 0b | |
| Secured OTP | 0=not support 1=support | | 11 | 0b | |
| Read Lock | 0=not support 1=support | | 12 | 0b | |
| Permanent Lock | 0=not support 1=support | | 13 | 1b | |
| Unused | | | 15:14 | 11b | |
| Unused | | | 31:16 | FFFFH | |



ACE25AA400G

Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Electrical Characteristics

Power-On Timing

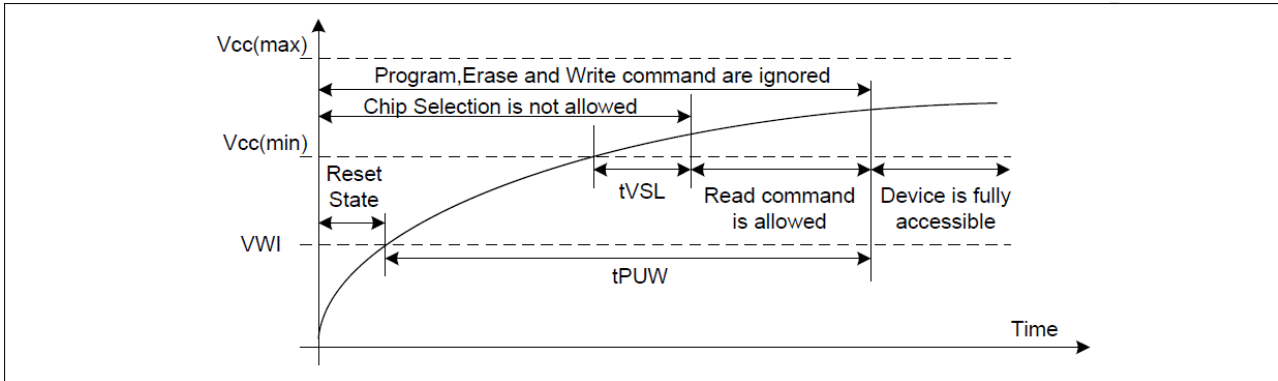


Table6. Power-Up Timing and Write Inhibit Threshold

| Symbol | Parameter | Min | Max | Unit |
|-----------|-------------------------------------|-----|-----|------|
| t_{VSL} | VCC(min) To CS# Low | 10 | | us |
| t_{PUW} | Time Delay Before Write Instruction | 1 | 10 | ms |
| V_{WI} | Write Inhibit Voltage | 1 | 2.5 | V |

Initial Delivery State

The device is delivered with the memory array erased: all bits are set to 1 (each byte contains FFH). The Status Register contains 00H (all Status Register bits are 0).

Data Retention and Endurance

| Parameter | Typical | Unit |
|-------------------------|---------|--------|
| Data Retention Time | 20 | Years |
| Erase/Program Endurance | 100K | Cycles |

Latch up Characteristics

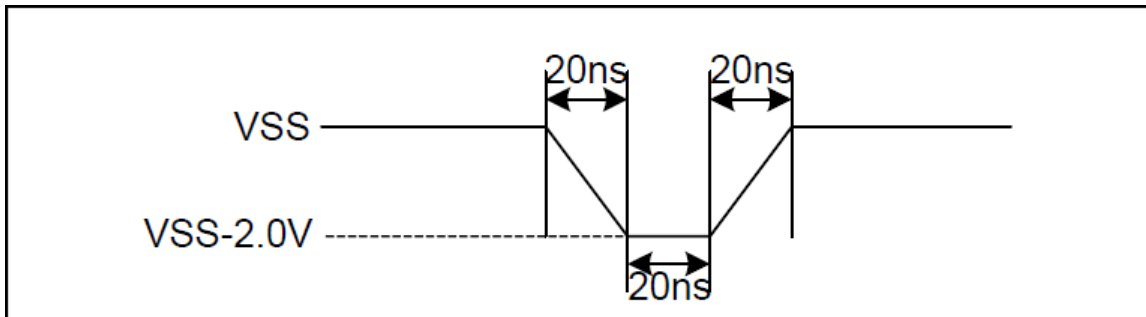
| Parameter | Min | Max |
|--|--------|----------|
| Input Voltage Respect To VSS On I/O Pins | -1.0V | VCC+1.0V |
| VCC Current | -100mA | 100mA |



Capacitance Measurement Condition

| Symbol | Parameter | Min | Typ | Max | Unit | Conditions |
|--------|---------------------------------|------------------|-----|-----|------|------------|
| CIN | Input Capacitance | | | 6 | pF | VIN=0V |
| COUT | Output Capacitance | | | 8 | pF | VOOUT=0V |
| CL | Load Capacitance | 30 | | | pF | |
| | Input Rise And Fall time | | | 5 | ns | |
| | Input Pulse Voltage | 0.1VCC to 0.8VCC | | | V | |
| | Input Timing Reference Voltage | 0.2VCC to 0.7VCC | | | V | |
| | Output Timing Reference Voltage | 0.5VCC | | | V | |

Maximum Negative Overshoot Waveform



Maximum Positive Overshoot Waveform

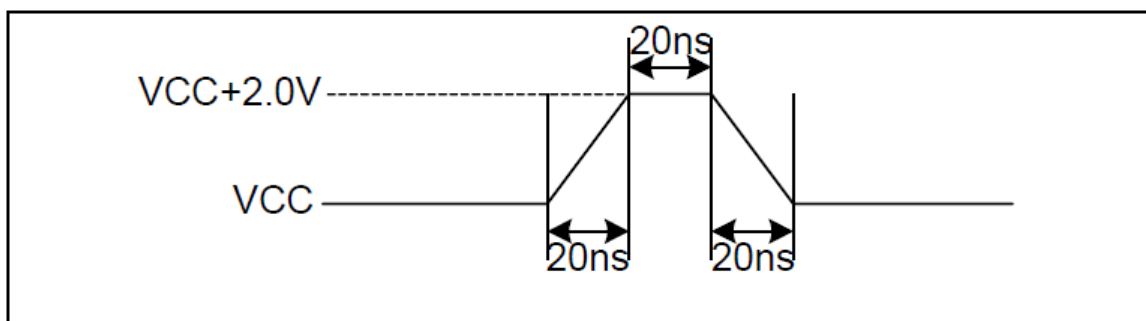


Figure35. Input Test Waveform and MeasurementLevel



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Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

DC Characteristics (T=-40°C~85°C, VCC=2.7~3.6V)

| Symbol | Parameter | Test Condition | Min. | Typ | Max. | Unit |
|------------------|-------------------------|---|---------|------|---------|------|
| I _{LI} | Input Leakage Current | | | | ±2 | μA |
| I _{LO} | Output Leakage Current | | | | ±2 | μA |
| I _{CC1} | Standby Current | CS#=VCC VIN=VCC or VSS | | 12 | 20 | μA |
| I _{CC2} | Deep Power-Down Current | CS#=VCC VIN=VCC or VSS | | 0.03 | 0.05 | μA |
| I _{CC3} | Operating Current(Read) | CLK=0.1VCC/0.9VCC at 120MHz ,Q=Open(*1I/O) | | 15 | 20 | mA |
| | | CLK=0.1VCC/0.9VCC at 80MHz,Open(*1,*2,4I/O) | | 13 | 18 | |
| | | CLK=0.1VCC/0.9VCC at 50MHz ,Q=Open(*1I/O) | | 5 | 7 | |
| I _{CC4} | Operating Current(PP) | CS#=VCC | | | 20 | mA |
| I _{CC5} | Operating Current(WRSR) | CS#=VCC | | | 20 | mA |
| I _{CC6} | Operating Current(SE) | CS#=VCC | | | 20 | mA |
| I _{CC7} | Operating Current(BE) | CS#=VCC | | | 20 | mA |
| V _{IL} | Input Low Voltage | | -0.5 | | 0.2VCC | V |
| V _{IH} | Input High Voltage | | 0.7VCC | | VCC+0.4 | V |
| V _{OL} | Output Low Voltage | I _{OL} =1.6mA | | | 0.4 | V |
| V _{OH} | Output High Voltage | I _{OH} =-100uA | VCC-0.2 | | | V |



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Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

AC Characteristics (T=-40°C~85°C, VCC=2.7~3.6V, C_L=30pf)

| Symbol | Parameter | Min. | Typ | Max. | Unit |
|--------|---|------|-----|------|------|
| fC | Serial Clock Frequency For: Fast Read(0BH),Dual Output(3BH) | | | 108 | MHz |
| fC1 | Serial Clock Frequency For: Dual I/O (BBH),Quad I/O(EBH),Quad Output(6BH) | | 80 | 108 | MHz |
| fR | Serial Clock Frequency For: Read(03H) | | | 80 | MHz |
| tCLH | Serial Clock High Time | 4 | | | ns |
| tCLL | Serial Clock Low Time | 4 | | | ns |
| tCLCH | Serial Clock Rise Time(Slew Rate) | 0.2 | | | V/ns |
| tCHCL | Serial Clock Fall Time(Slew Rate) | 0.2 | | | V/ns |
| tSLCH | CS# Active Setup Time | 5 | | | ns |
| tCHSH | CS# Active Hold Time | 5 | | | ns |
| tSHCH | CS# Not Active Setup Time | 5 | | | ns |
| tCHSL | CS# Not Active Hold Time | 5 | | | ns |
| tSHSL | CS# High Time (read/write) | 20 | | | ns |
| tSHQZ | Output Disable Time | | | 6 | ns |
| tCLQX | Output Hold Time | 1 | | | ns |
| tDVCH | Data In Setup Time | 2 | | | ns |
| tCHDX | Data In Hold Time | 2 | | | ns |
| tHLCH | Hold# Low Setup Time(relative to Clock) | 5 | | | ns |
| tHHCH | Hold# High Setup Time(relative to Clock) | 5 | | | ns |
| tCHHL | Hold# High Hold Time(relative to Clock) | 5 | | | ns |
| tCHHH | Hold# Low Hold Time(relative to Clock) | 5 | | | ns |
| tHLQZ | Hold# Low To High-Z Output | | | 6 | ns |
| tHHQX | Hold# Low To Low-Z Output | | | 6 | ns |
| tCLQV | Clock Low To Output Valid | | | 6.5 | ns |
| tWHSL | Write Protect Setup Time Before CS# Low | 20 | | | ns |
| tSHWL | Write Protect Hold Time After CS# High | 100 | | | ns |
| tDP | CS# High To Deep Power-Down Mode | | | 0.1 | us |
| tRES1 | CS# High To Standby Mode Without Electronic Signature Read | | | 20 | us |
| tRES2 | CS# High To Standby Mode With Electronic Signature Read | | | 20 | us |



ACE25AA400G

Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

| | | | | | |
|--------|---|--|-----------|----------|----|
| tRST_R | CS# High To Next Command After Reset (from read) | | | 20 | us |
| tRST_P | CS# High To Next Command After Reset (from program) | | | 20 | us |
| tRST_E | CS# High To Next Command After Reset (from erase) | | | 12 | ms |
| tW | Write Status Register Cycle Time | | 60 | 500 | ms |
| tPP | Page Programming Time | | 0.4 | 0.75 | ms |
| tSE | Sector Erase Time | | 60 | 500 | ms |
| tBE | Block Erase Time(32K Bytes/64K Bytes) | | 0.15/0.25 | 0.5/0.75 | s |
| tCE | Chip Erase Time | | 1.25 | 5 | s |

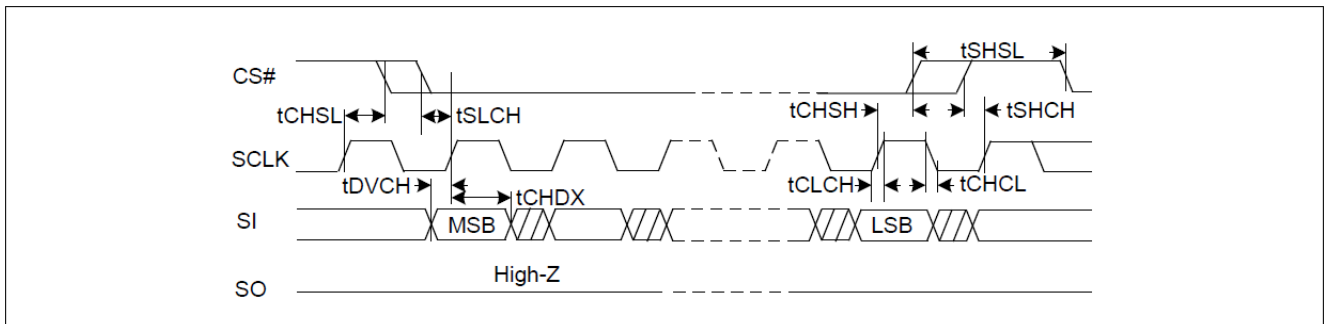


Figure36. Serial Input Timing

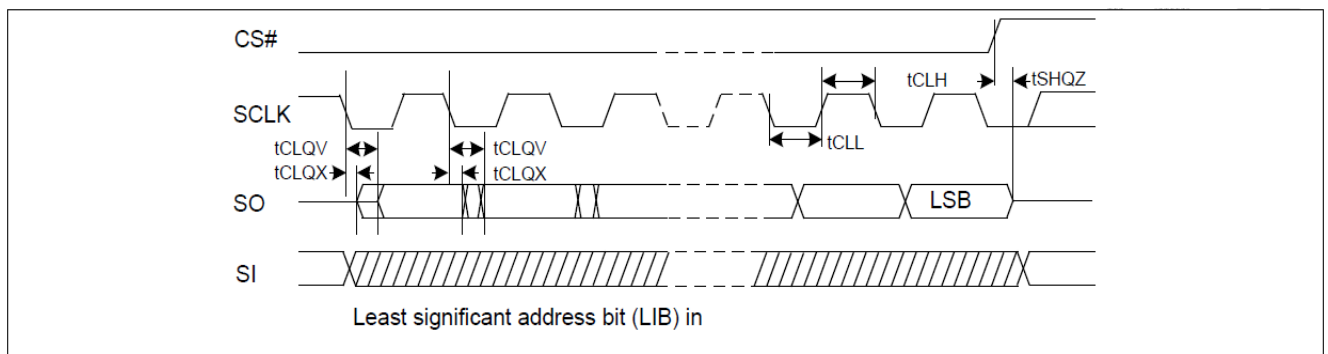


Figure37. Output Timing

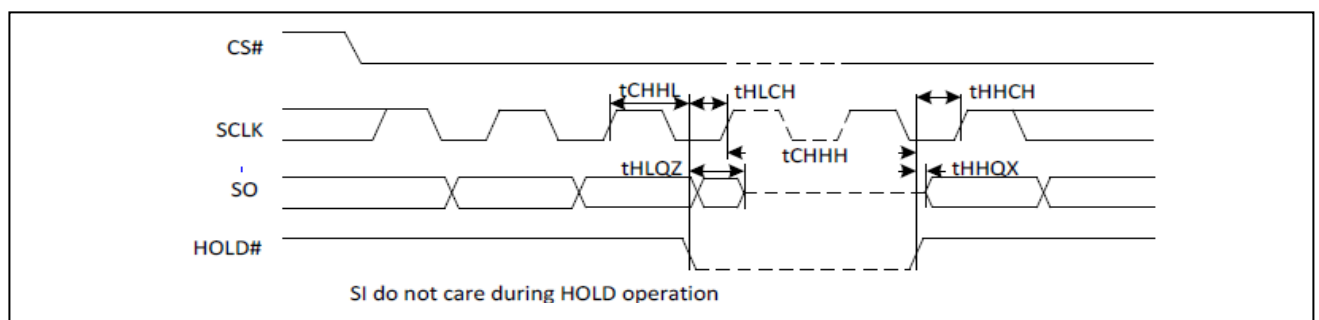


Figure38. Hold Timing

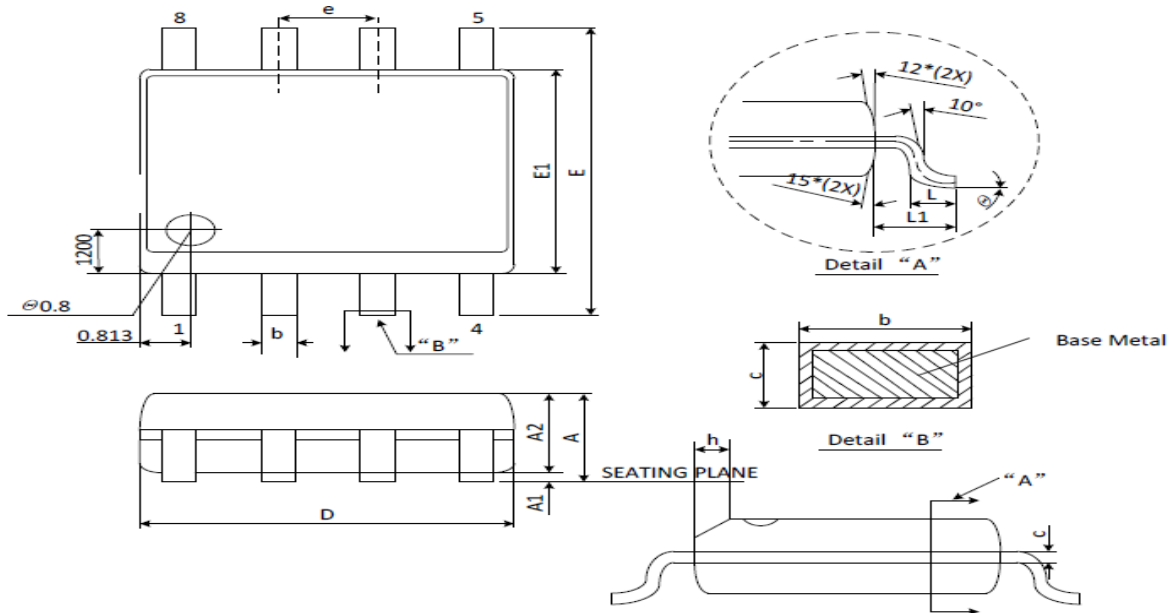


ACE25AA400G

Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Packaging information

SOP-8



| Symbol | Dimensions In Millimeters | | |
|--------|---------------------------|-------|-------|
| | Min | Norm | Max |
| A | 1.350 | | 1.750 |
| A1 | 0.100 | | 0.250 |
| A2 | 1.300 | | 1.500 |
| b | 0.330 | | 0.510 |
| c | 0.190 | | 0.250 |
| D | 4.700 | 4.900 | 5.000 |
| E1 | 3.800 | 3.900 | 4.000 |
| e | | 1.270 | |
| E | 5.800 | 6.000 | 6.200 |
| h | 0.250 | 0.350 | 0.500 |
| L | 0.508 | 0.635 | 0.762 |
| L1 | 0.837 | 1.040 | 1.243 |
| θ | 0° | | 8° |

Note:

1. Coplanarity: 0.1mm
2. Max allowable mold flash is 0.15mm at the package ends. 0.25mm between leads.
3. All dimensions follow JEDEC MS-012 standard.

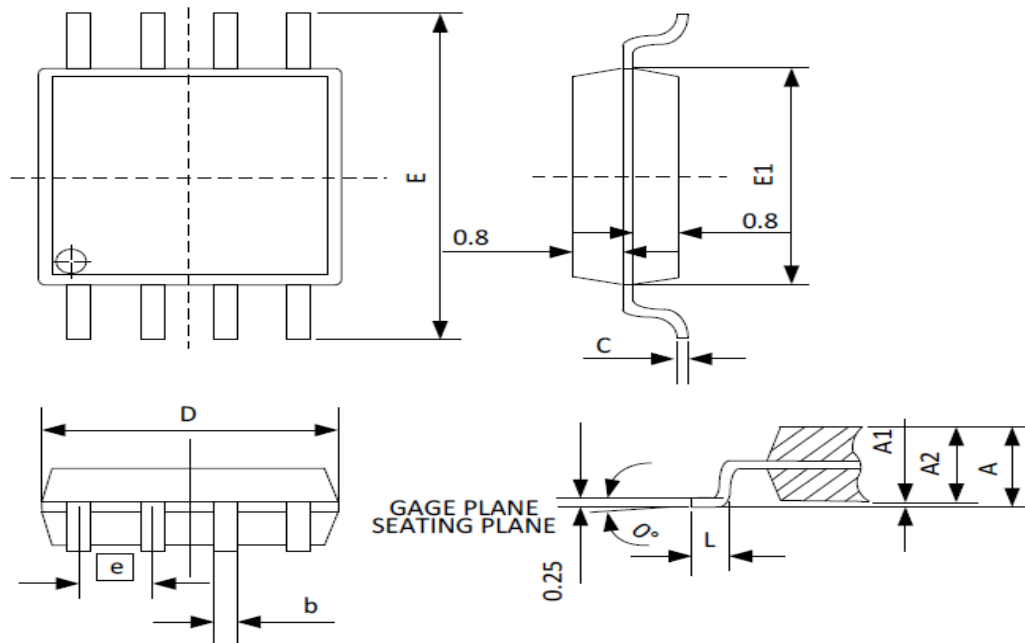


ACE25AA400G

Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Packaging information

SOP-8L (208mil)



| Symbol | Dimensions In Millimeters | | |
|-------------|---------------------------|-------|-------|
| | Min | Norm | Max |
| A | 1.750 | 1.950 | 2.160 |
| A1 | 0.050 | 0.150 | 0.250 |
| A2 | 1.700 | 1.800 | 1.910 |
| b | 0.350 | 0.420 | 0.480 |
| c | 0.190 | 0.200 | 0.250 |
| D | 5.130 | 5.230 | 5.330 |
| E | 7.700 | 7.900 | 8.100 |
| E1 | 5.180 | 5.280 | 5.380 |
| $\square e$ | 1.270 BSC | | |
| L | 0.500 | 0.650 | 0.800 |
| theta | 0° | | 8° |

Note:

1. JEDEC Outline : N/A
2. Coplanarity: 0.1mm
3. Max allowable mold flash is 0.15mm at the package ends. 0.25mm between leads.

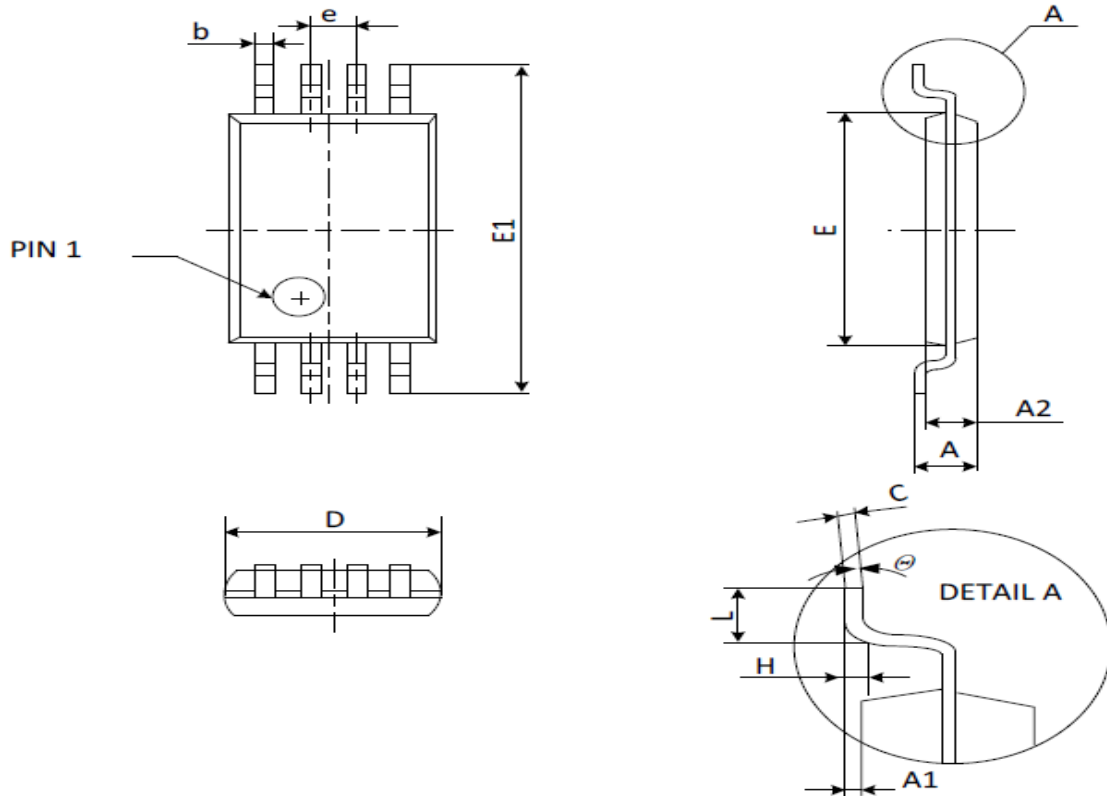


ACE25AA400G

Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Packaging information

TSSOP-8



| Symbol | Dimensions In Millimeters | | Dimensions In Inches | |
|--------|---------------------------|-------|----------------------|-------|
| | Min | Max | Min | Max |
| D | 2.900 | 3.100 | 0.114 | 0.122 |
| E | 4.300 | 4.500 | 0.169 | 0.177 |
| b | 0.190 | 0.300 | 0.007 | 0.012 |
| c | 0.090 | 0.200 | 0.004 | 0.008 |
| E1 | 6.250 | 6.550 | 0.246 | 0.258 |
| A | | 1.200 | | 0.047 |
| A2 | 0.800 | 1.000 | 0.031 | 0.039 |
| A1 | 0.050 | 0.150 | 0.002 | 0.006 |
| e | 0.65 (BSC) | | 0.026 (BSC) | |
| L | 0.500 | 0.700 | 0.020 | 0.028 |
| H | 0.25 (TYP) | | 0.01 (TYP) | |
| θ | 1° | 7° | 1° | 7° |

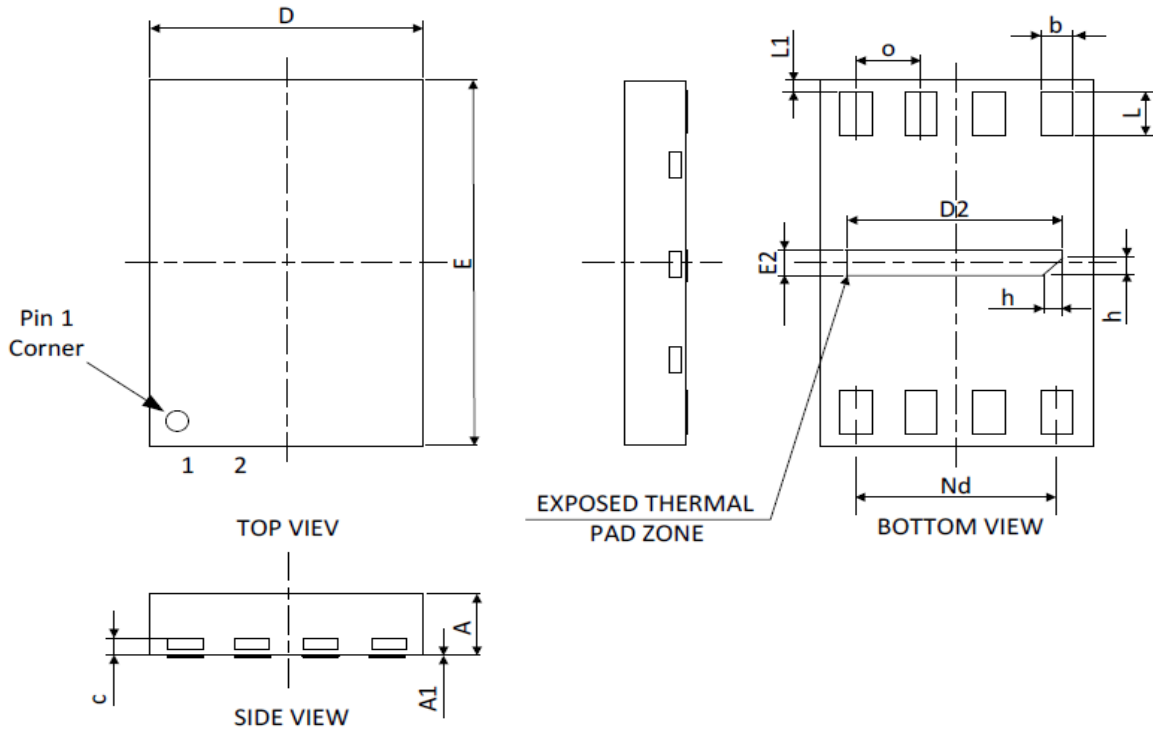


ACE25AA400G

Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Packaging information

USON3*2-8



| Symbol | Dimensions In Millimeters | | |
|--------|---------------------------|-------|-------|
| | Min | Norm | Max |
| A | 0.500 | 0.550 | 0.600 |
| A1 | 0.000 | 0.020 | 0.050 |
| b | 0.180 | 0.250 | 0.030 |
| c | 0.100 | 0.150 | 0.200 |
| D | 1.900 | 2.000 | 2.100 |
| D2 | 1.500 | 1.600 | 1.700 |
| e | 0.500BSC | | |
| Nd | 1.500BSC | | |
| E | 2.900 | 3.000 | 3.100 |
| E2 | 0.100 | 0.200 | 0.300 |
| L | 0.300 | 0.350 | 0.400 |
| L1 | 0.050 | 0.100 | 0.150 |
| h | 0.050 | 0.150 | 0.250 |



ACE25AA400G
Serial NOR Flash Memory 4M bits 3.0V Quad I/O Serial Flash Memory with 4KB Uniform Sector

Notes

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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